

R&D Status of Monolithic SOI Pixel Sensor for Vertex Detector

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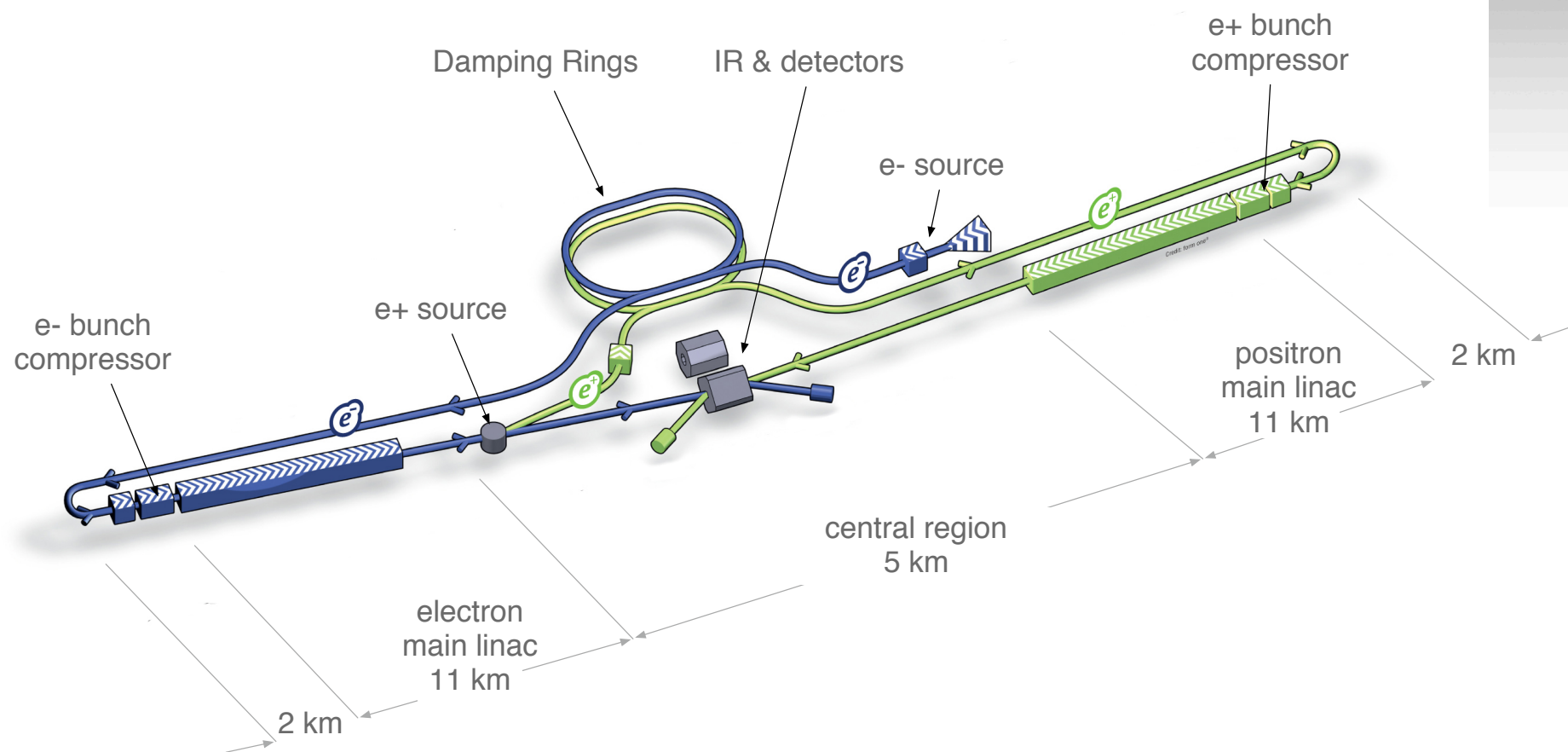
H. Murayama, S. Iwanami, K. Hara (Univ. Tsukuba), A. Takeda (Univ. Miyazaki)

and SOI PIXEL R&D Group

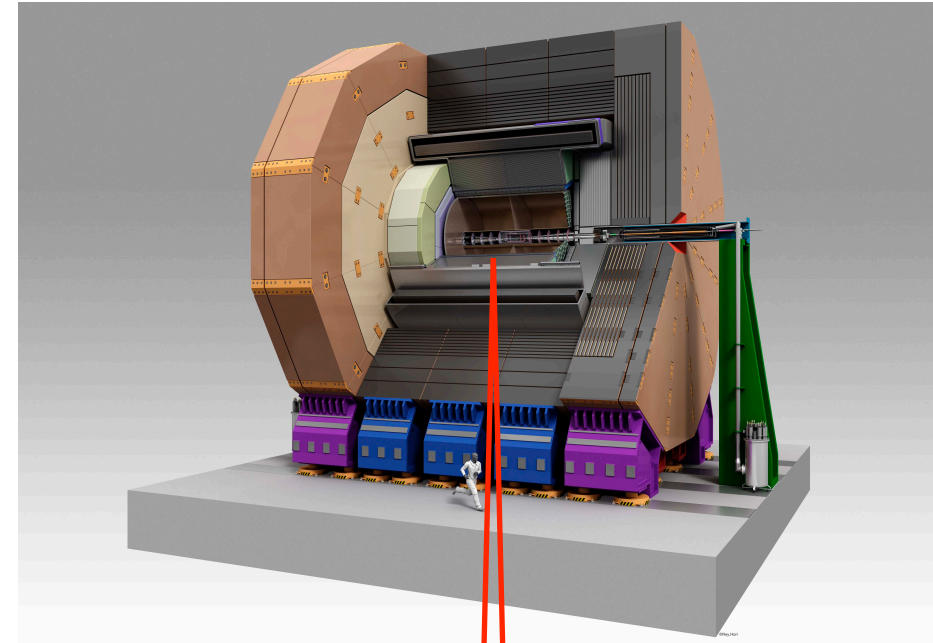
ILC Experiment

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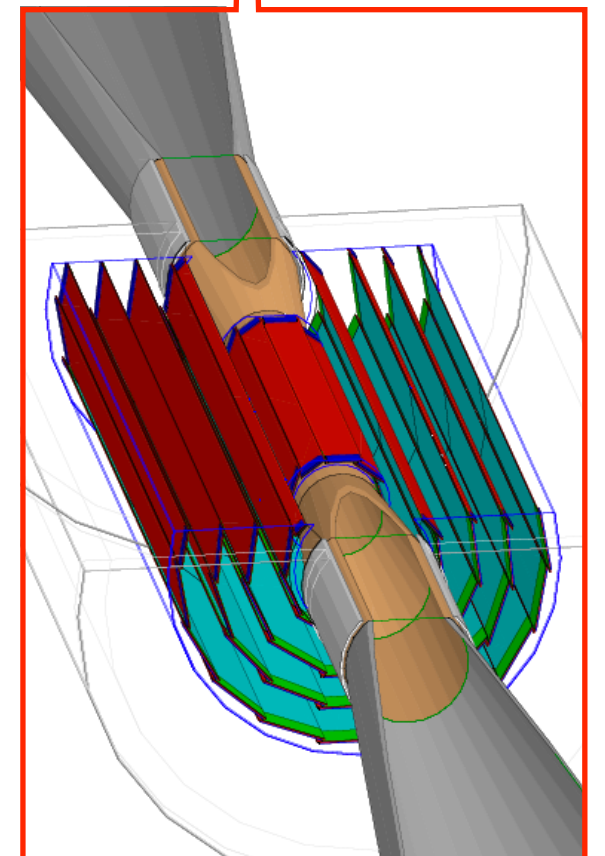
- e^+e^- linear collider
- Center of mass energy: 250 - 500 GeV (extendable to 1 TeV)
- Precise measurement of the Higgs boson
- Search for beyond the Standard Model



ILC detector concept (ILD)



Vertex detector geometry (VTX-SL)

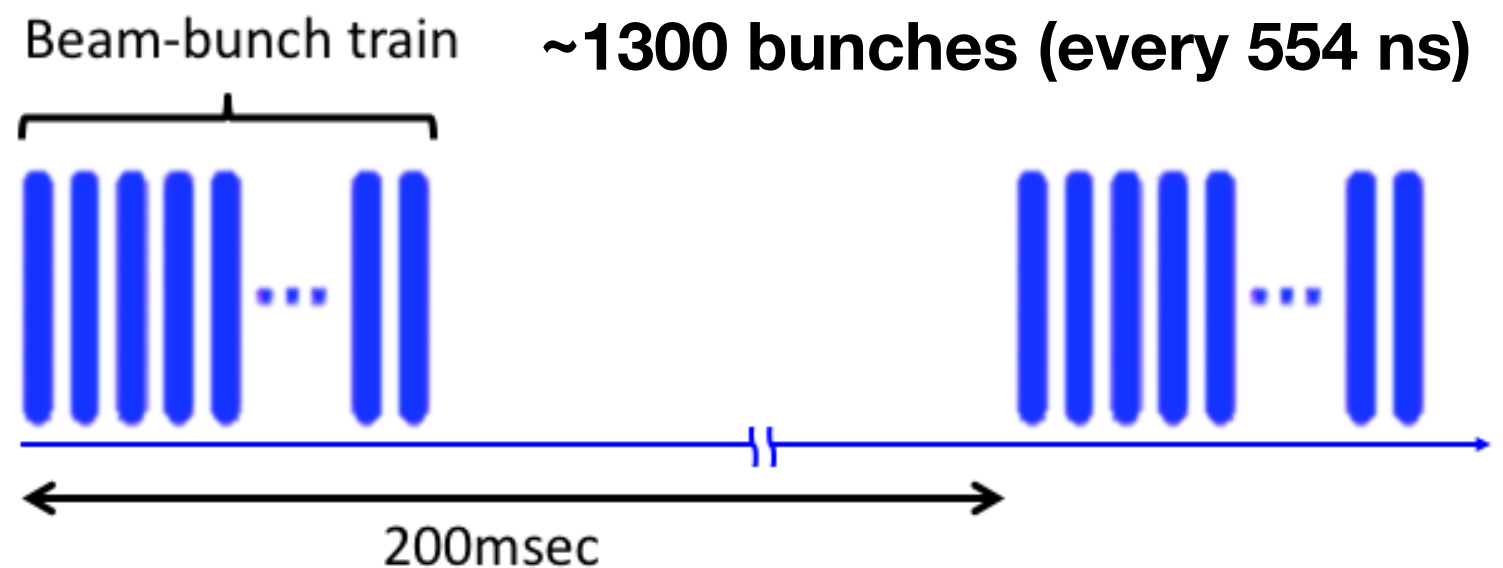


ILC Vertex detector

Requirements:

- 1) Single point resolution: better than $3\ \mu\text{m}$
Pixel size: $\sim 20 \times 20\ \mu\text{m}^2$
- 2) Time resolution: single-crossing (554 ns interval) time resolution
- 3) Detector occupancy: $< 2\%$
- 4) Low material budget: $X \leq 0.1 - 0.2\% X_0 / \text{Layer}$
corresponds to $\sim 100 - 200\ \mu\text{m Si}$, including supports, cables and cooling
low-power ASICs ($\sim 50\ \text{mW}/\text{cm}^2$) + gas-flow cooling
- 5) Radiation hardness:
TID : $< 1\ \text{kGy} / \text{year}$
NIEL: $< 10^{11}\ 1\text{MeV } n_{\text{eq}} / \text{cm}^2 / \text{year}$

We are designing and evaluating
prototype pixel sensor with SOI technology
to fulfill the requirements.



SOI Pixel Detector

SOI: Silicon-on-Insulator technology

Utilize 0.2 μm FD-SOI CMOS process by Lapis Semiconductor Co. Ltd.

SOI Pixel Detector: Monolithic type detector

- LSI is processed on Buried Oxide layer (BOX)
- Smaller pixel size, complex circuit in pixel
- Low material budget
- High speed, low power
- Less single event effects (SEE) probability
- Low cost

Double SOI Pixel Detector

Middle Si layer suppresses

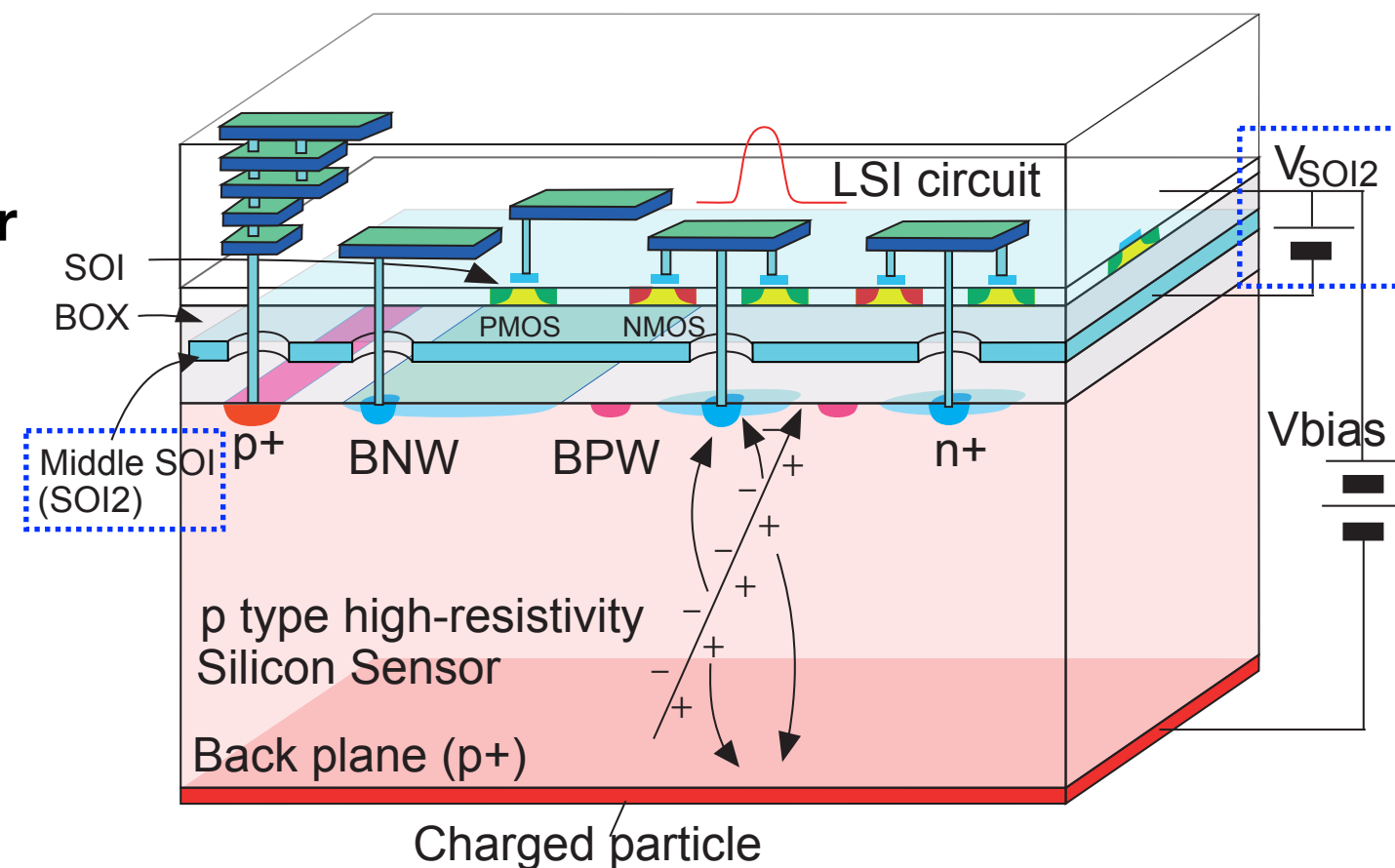
- Back gate effect
- Sensor-Circuit cross talk

Middle Si layer shields coupling between sensor and circuit.
It is useful for analog and digital mixed circuit in pixel.

- Radiation damage (TID)

It is able to compensate electric field generated by trapped holes in the BOX.
It can be used in high radiation environment ($\sim 1\text{MGy}$).
(K. Hara et. al., TIPP2017, May 22-27, 2017, Beijing)

Double SOI Pixel Detector



Sensor thickness: 50 - 500 μm
Sensor Resistivity: $> 1 \text{ k}\Omega\cdot\text{cm}$
SOI2 thickness: 150 μm (n-type)
SOI2 Resistivity: $< 10 \Omega\cdot\text{cm}$

Functions for ILC Vertex Detector

Necessary functions for the ILC vertex detector:

- Single point resolution

Pixel size: less than $20\ \mu\text{m}$

Calculate weighted center of charges (Charges are spread among multi pixels).

→ Record an analog signal of a hit.

- Timing resolution

Bunch crossing occurs every 554 ns in 1-msec-long bunch train with an interval 200 ms.

Identify a collision bunch of a hit to reconstruct a event.

→ Record a time stamp of a hit.

- Detector occupancy

Hit information have to hold during 1 beam-bunch train.

Increase detector occupancy.

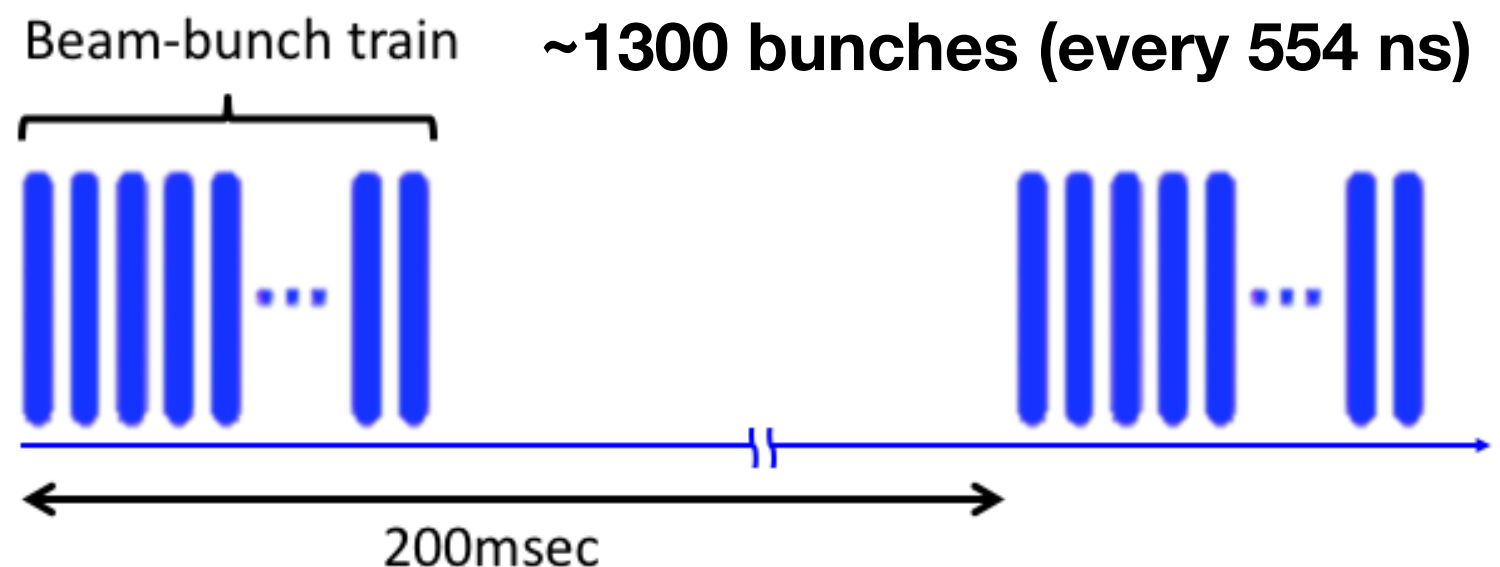
→ Need multiple memories

- High speed data transfer

Data have to be send to backend before next bunch train injection.

→ Reduce a data to transfer.

We designed a prototype pixel detector
SOFIST.



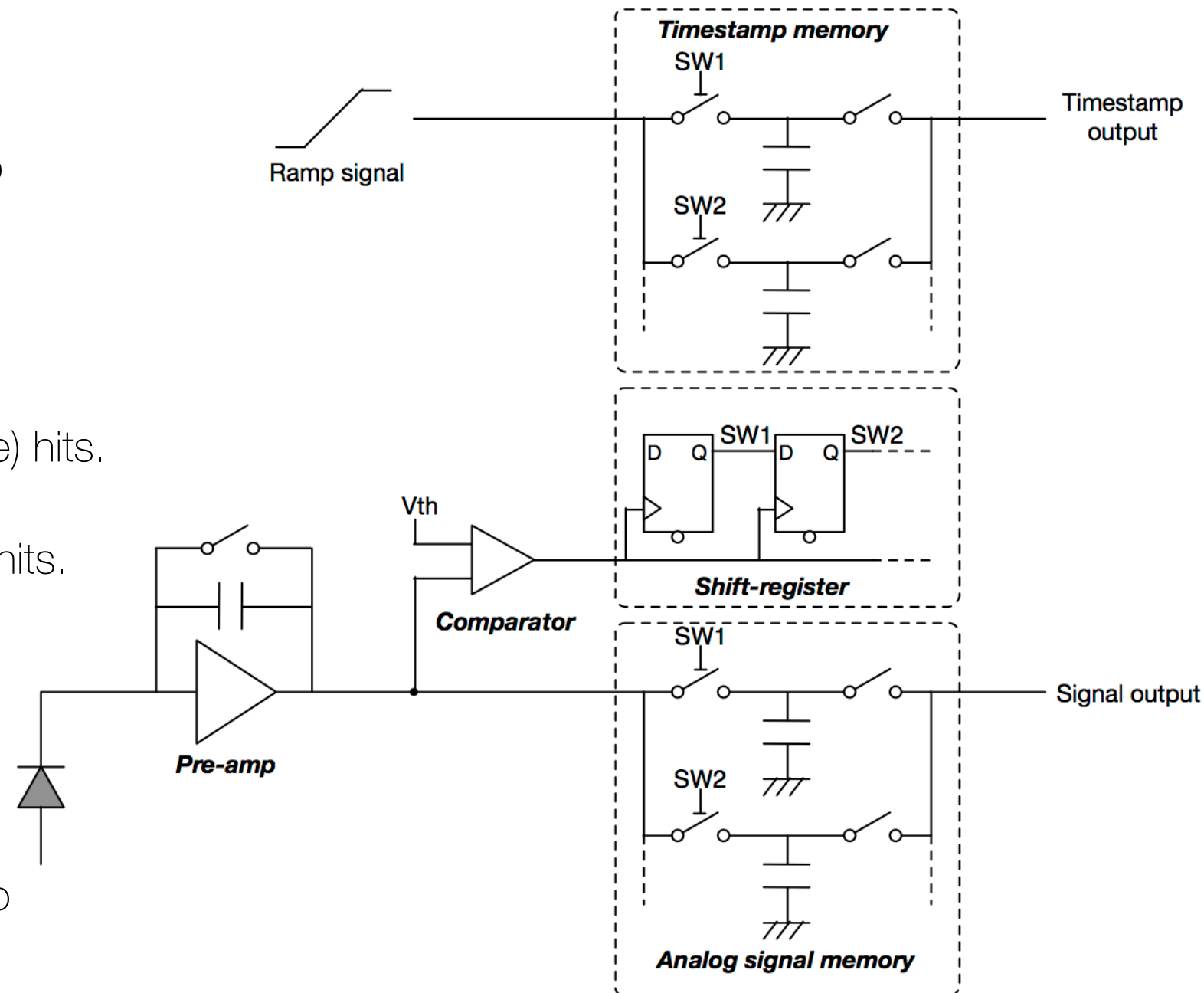
Architecture of SOFIST

In a Pixel

- Pre-amplifier
- Comparator
 - Keep the analog signal and time stamp if a signal exceeds a threshold V_{th} .
- Shift register
 - Latch for multiple memories.
- Analog signal memory
 - Store signal charges up to two (or more) hits.
- Time stamp circuit
 - Store time stamps up to two (or more) hits.

On Chip

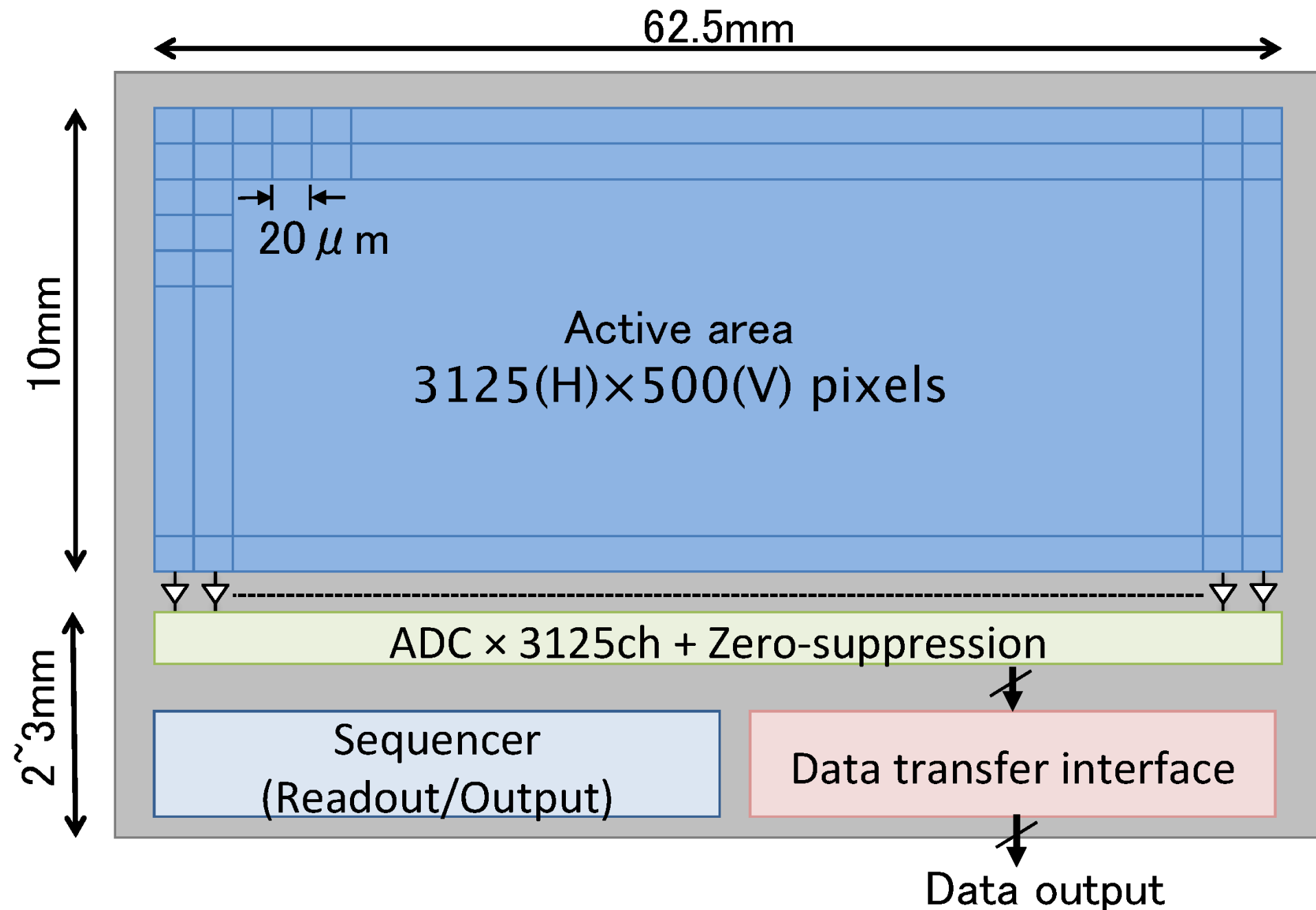
- Column ADC
 - Digitize analog signal and time stamp.
- Zero-Suppression logic
 - Extract hit pixels and reduce the data to transfer to backend.



SOI sensor for ILC: SOFIST

SOFIST: SOi sensor for Fine measurement of Space and Time

Conceptual SOI pixel sensor for the ILC (inner most layer of the vertex detector).



SOFIST

SOFIST

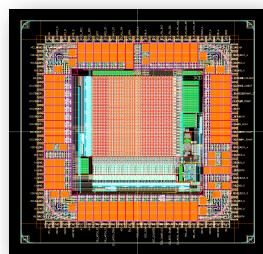
ver.1

ver.2

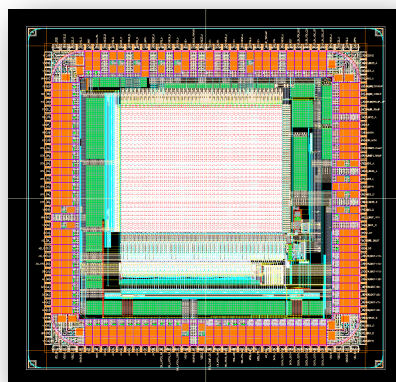
ver.3

ver.4 (3D)

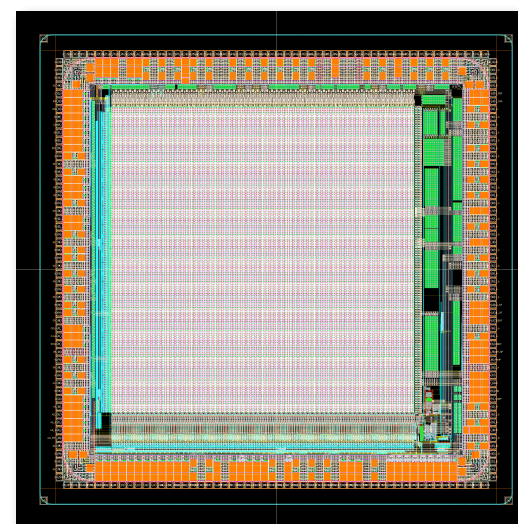
**Beam test at FNAL
in Jan. 2017
Analog signal**



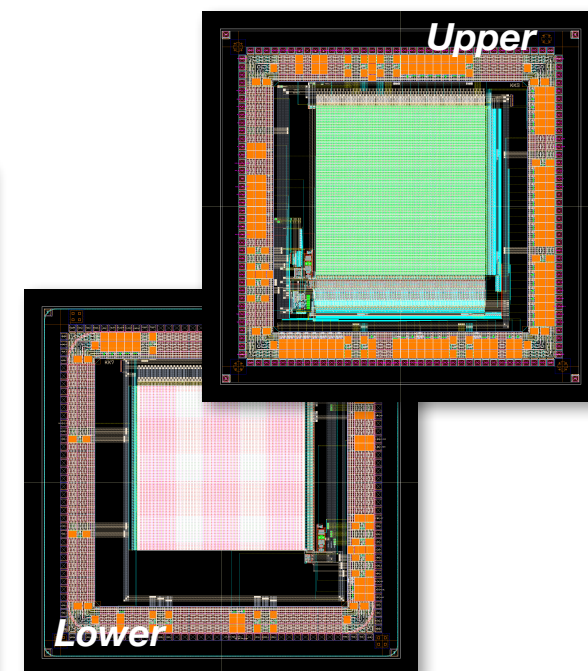
**Beam test at FNAL
in Feb. 2018
Analog signal or
Timestamp**



**Beam test at FNAL
in Feb. 2019
Analog signal and
Timestamp**



**Beam test at FNAL
in Feb. 2020**



Chip Size (mm ²)	2.9 × 2.9	4.45 × 4.45	6 × 6	4.45 × 4.45
Pixel Size (μm ²)	20 × 20	25 × 25	30 × 30	20 × 20
Pixel Array	50 × 50 (Analog Signal)	64 × 64 (Time Stamp) 16 × 64 (Analog Signal)	128 × 128 (Analog signal and Time stamp)	104 × 104 (Analog signal and Time stamp)
Functions (Pixel)	Pre. Amplifier (CSA) Analog signal memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 2) Analog signal memory (2 hits) or Time stamp memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)
Functions (On Chip)	Column ADC (8 bit)	Column ADC (8 bit) Zero-suppression logic	Column ADC (8 bit)	Column ADC (8 bit)
Wafer	FZ <i>n</i> -type (Single SOI)	Cz <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)
Wafer Resistivity (kΩ·cm)	2 ≤	1 ≤	3 - 10	3 - 10
Status	Delivered (Dec. 2015) Position resolution ~1.4 μm	Delivered (Jan. 2017) Time resolution ~1.55 μs	Delivered (May. 2018) Time resolution ~1.92 μs	Delivered (Jan. 2019 ~) Under evaluation

SOFIST3

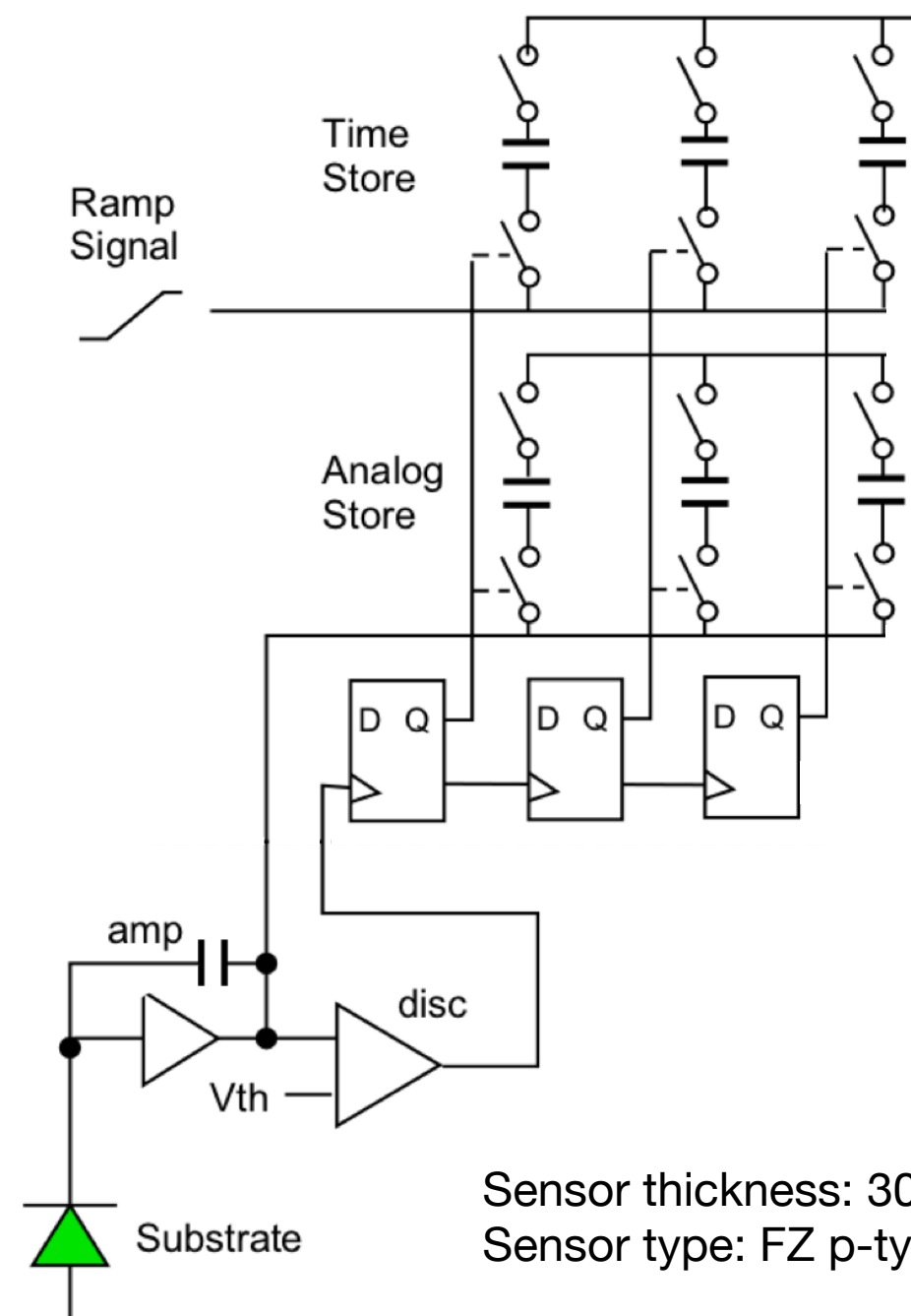
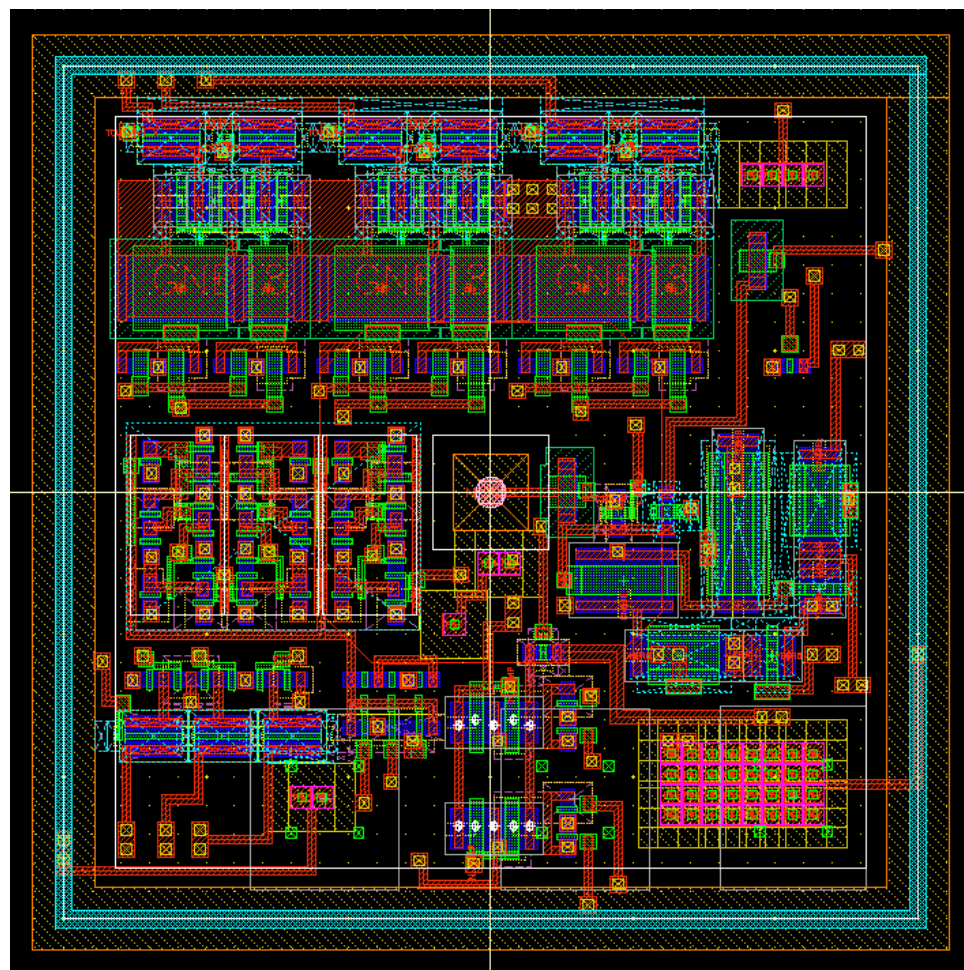
Pixel

- Pre. amplifier (Charge sensitive amplifier)
- Comparator (Chopper inverter)
- Shift register (three hits)
- Analog signal memories (three hits)
- Time stamp memories (three hits)

On chip

8 bit column ADC

Pixel size: $30 \times 30 \mu\text{m}^2$



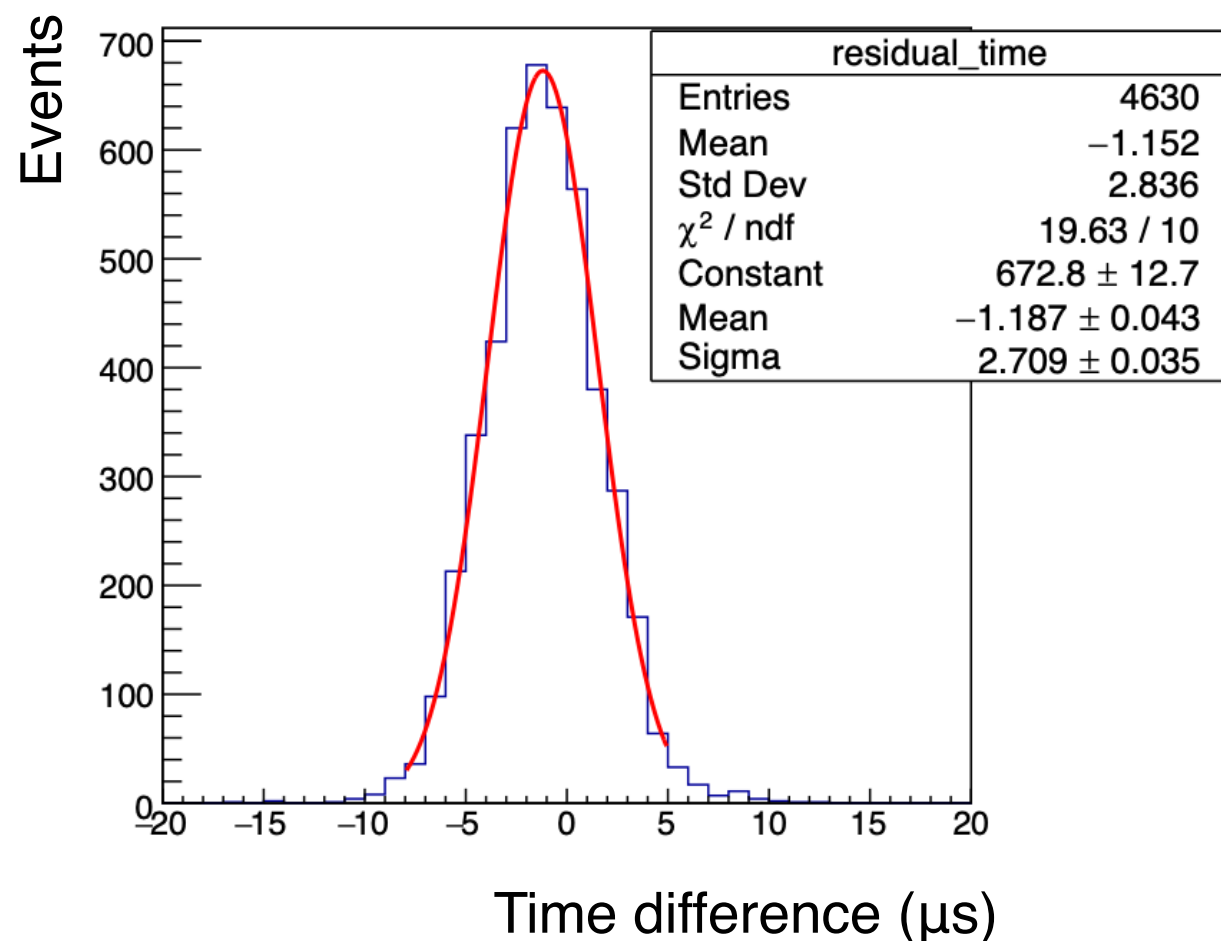
Sensor thickness: 300 or 65 μm
Sensor type: FZ p-type, DSOI

All necessary functions which are the same as SOFIST4 are implemented into a pixel.
Evaluation of pixel circuit is the main purpose of SOFIST3 due to large size pixel ($30 \times 30 \mu\text{m}^2$)

SOFIST3

Timestamp residual

Timestamp difference between #1 and #4.



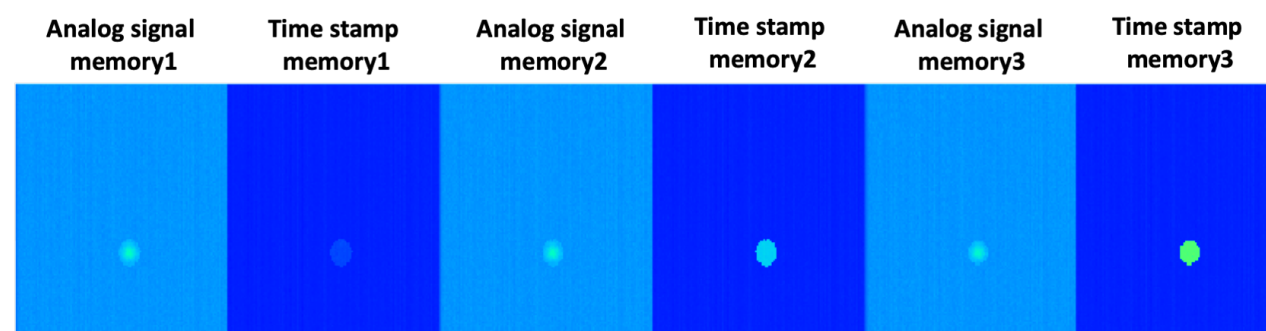
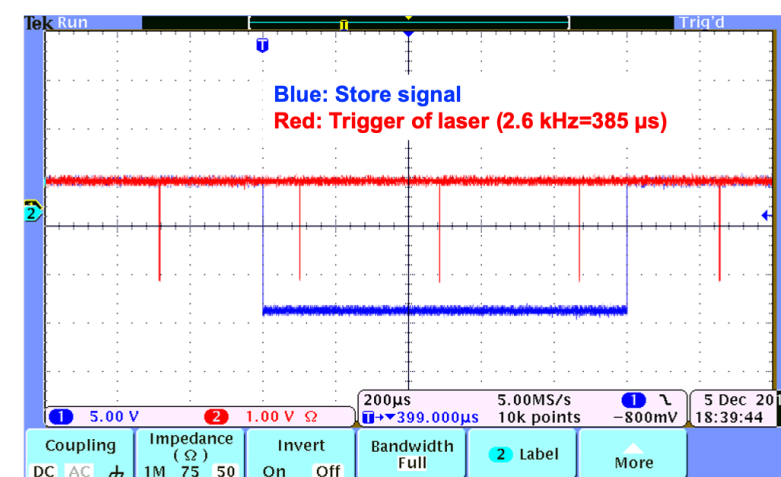
Intrinsic resolution: $2.71/\sqrt{2} \sim 1.92 \mu\text{s}$

Sensor Thickness: $300 \mu\text{m}$

Multi-memory readout test

SOFIST3 has three hit, analog signal and timestamp memories.

Multi-memory readout scheme was tested by injecting a IR laser three times in a 1 ms period.



Analog signal

Represent stable laser pulses (~ 180 ADC).

Timestamp

Show different timing of the laser injection (110, 490, 880 ADC).

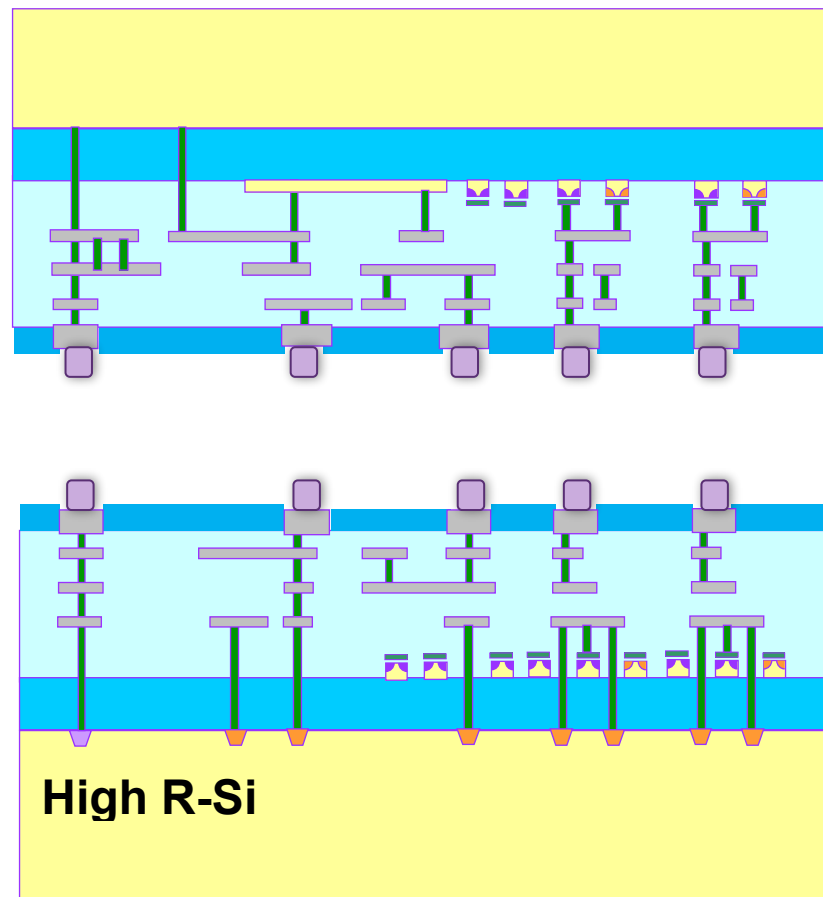
SOI Based 3D Stacking

Two SOI chips are connected by micro bump (3 μm diameter) pixel by pixel.

→ Keep pixel size small and implement complex circuit three dimensionally.

Detail of technology is shown by I. Kurachi (KEK) today [C06].

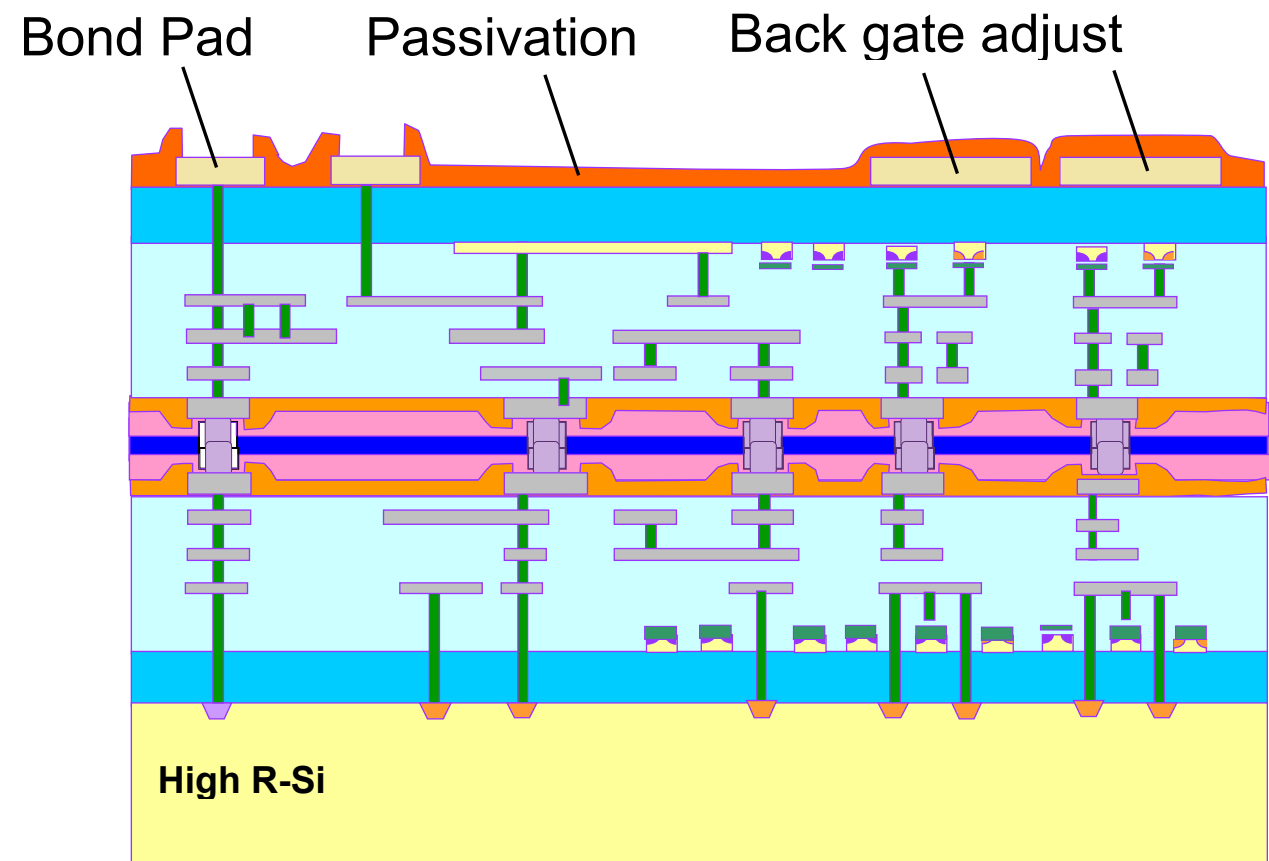
Upper



Lower

Lower Chip (Pixel): used as sensor and implement analog circuit in a pixel.

Upper Chip (Pixel): sensor layer is removed by wet etching and then formed Al pad for wire bonding on the BOX. digital circuits/memories are implemented in a pixel.



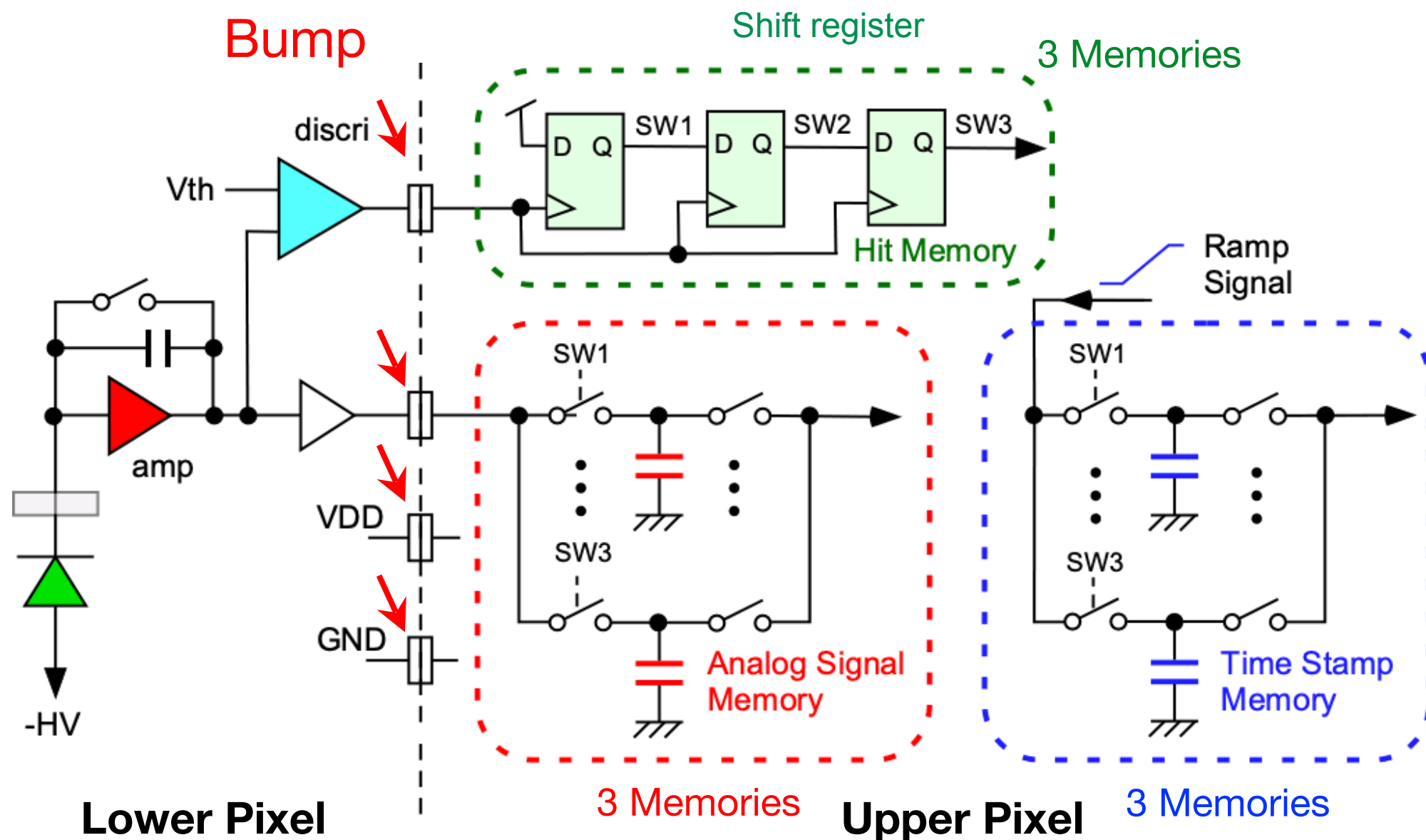
SOFIST4 Pixel

All necessary functions are implemented in a pixel.

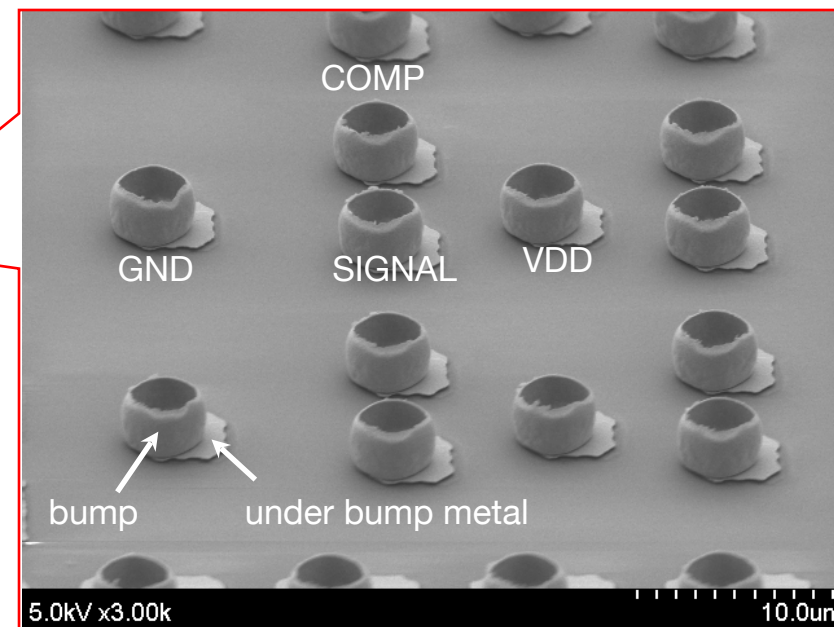
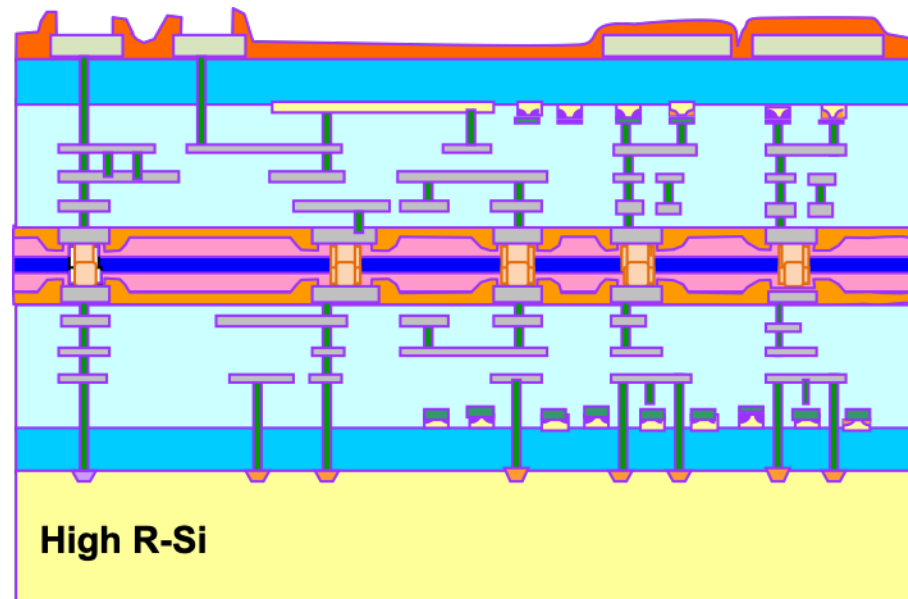
Lower pixel: Pre. amplifier and comparator

Upper pixel: Hit, Analog signal and Timestamp memories (up to 3 hits)

Output of pre. amplifier and comparator are sent to upper pixel via micro bump.



Au Micro Cylinder Bump

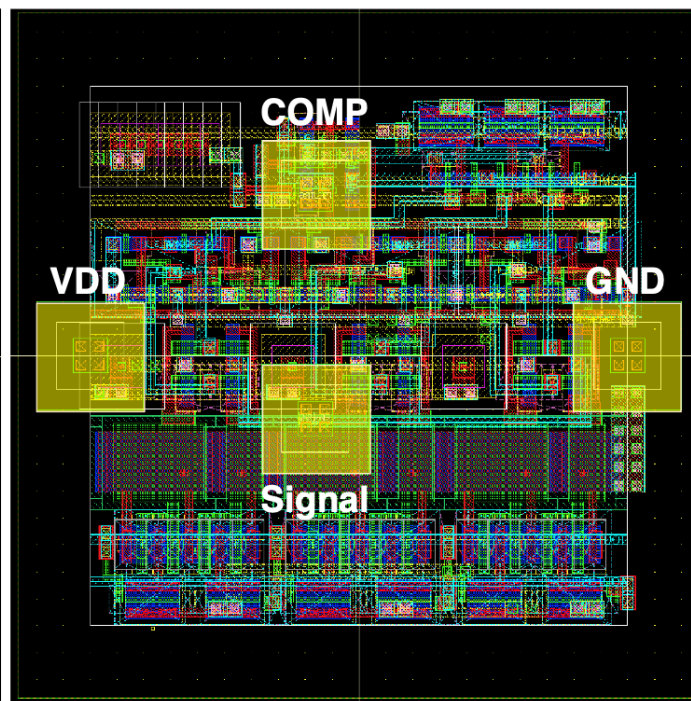
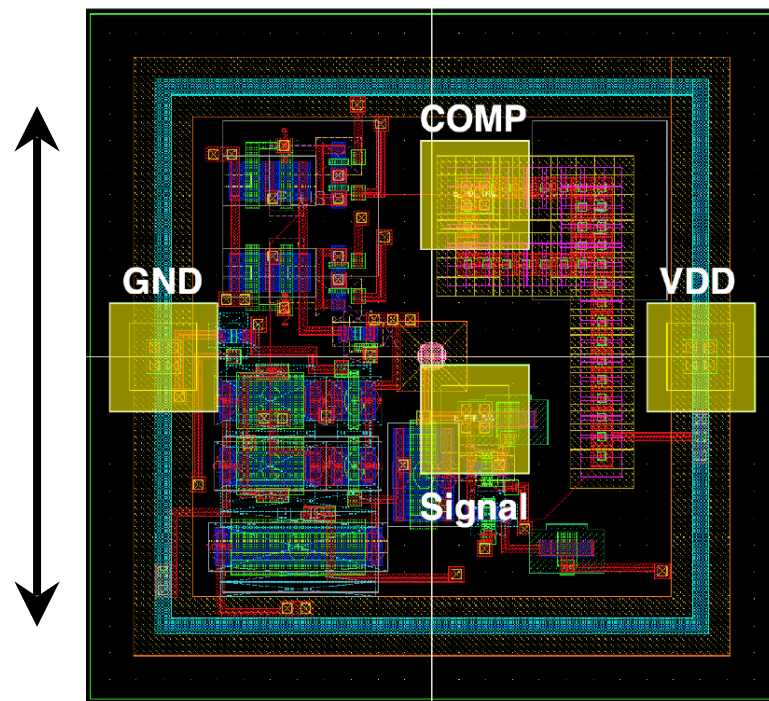


Au cylinder bump
Diameter: 3μm
(by T-Micro)

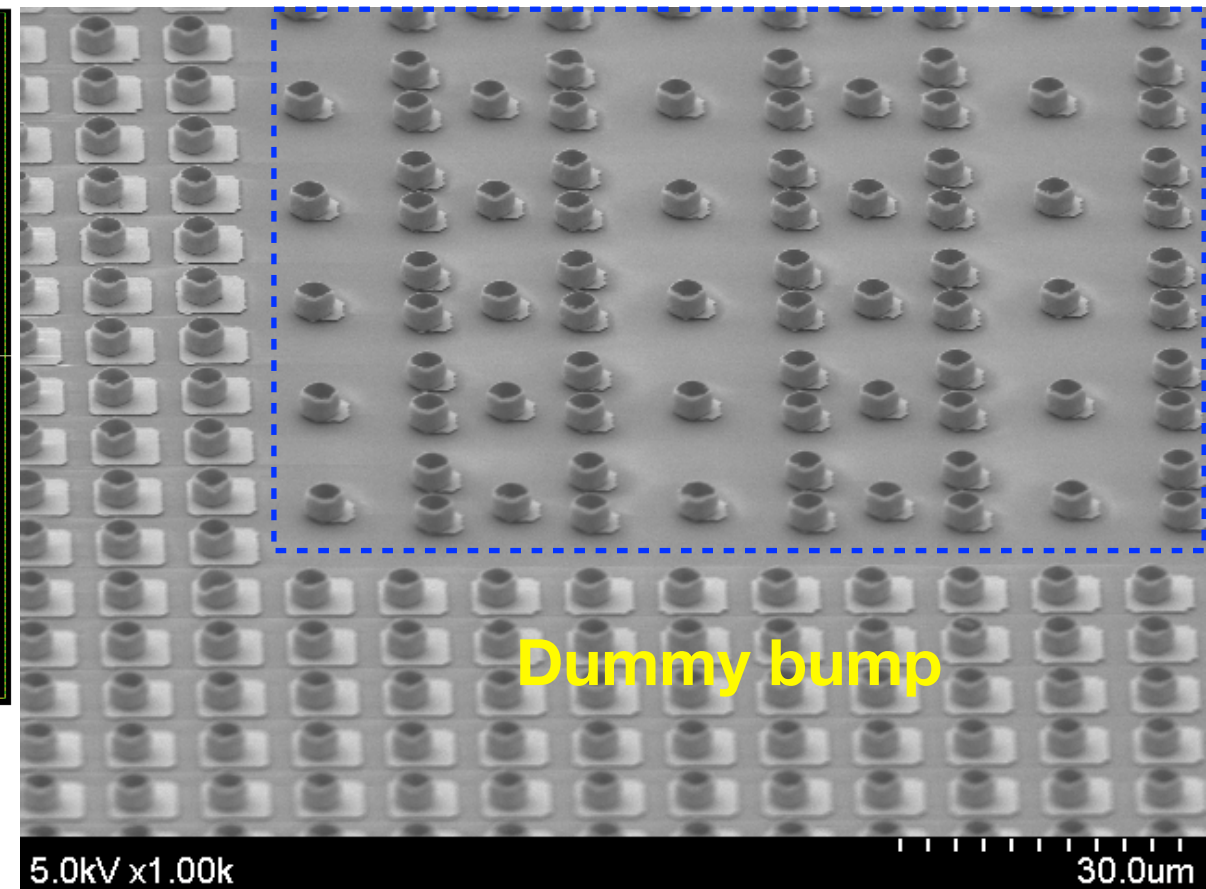
Lower pixel

Upper pixel

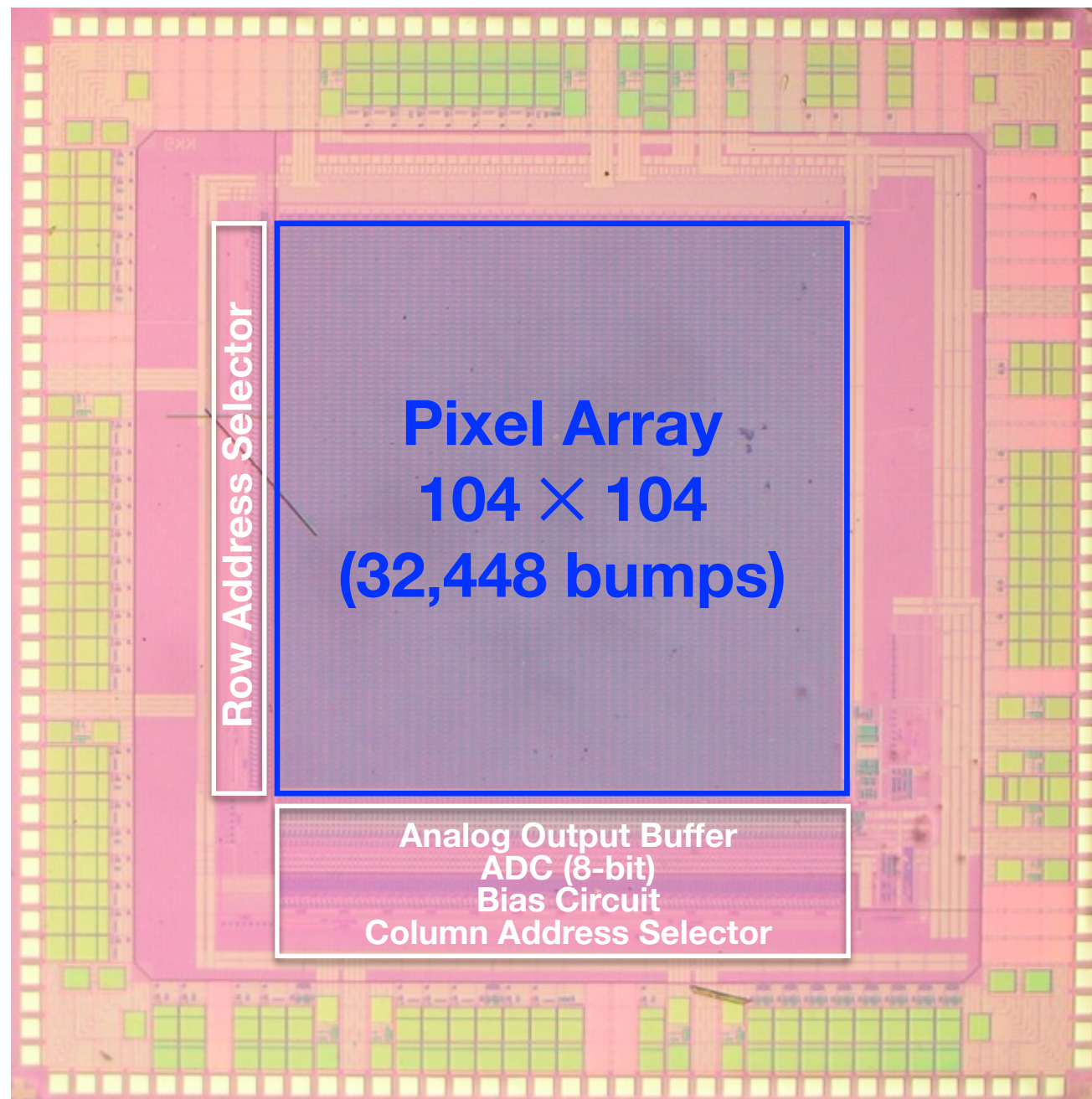
Pixel array



$20 \times 20 \mu\text{m}^2$



SOFIST4 Chip



$4.45 \times 4.45 \text{ mm}^2$

Design:

Chip size: $4.45 \times 4.45 \text{ mm}^2$

Pixel size: $20 \times 20 \mu\text{m}^2$

Active area: $2.08 \times 2.08 \text{ mm}^2$

Sensor type: Double SOI, FZ *p*-type

Sensor thickness: $300 \mu\text{m}$

Sensor resistivity: $3 - 10 \text{ k}\Omega \cdot \text{cm}$

Memory: Analog 3 hits

Timestamp 3 hits

Hit 3 hits

On-Chip: 8-bit Column ADC

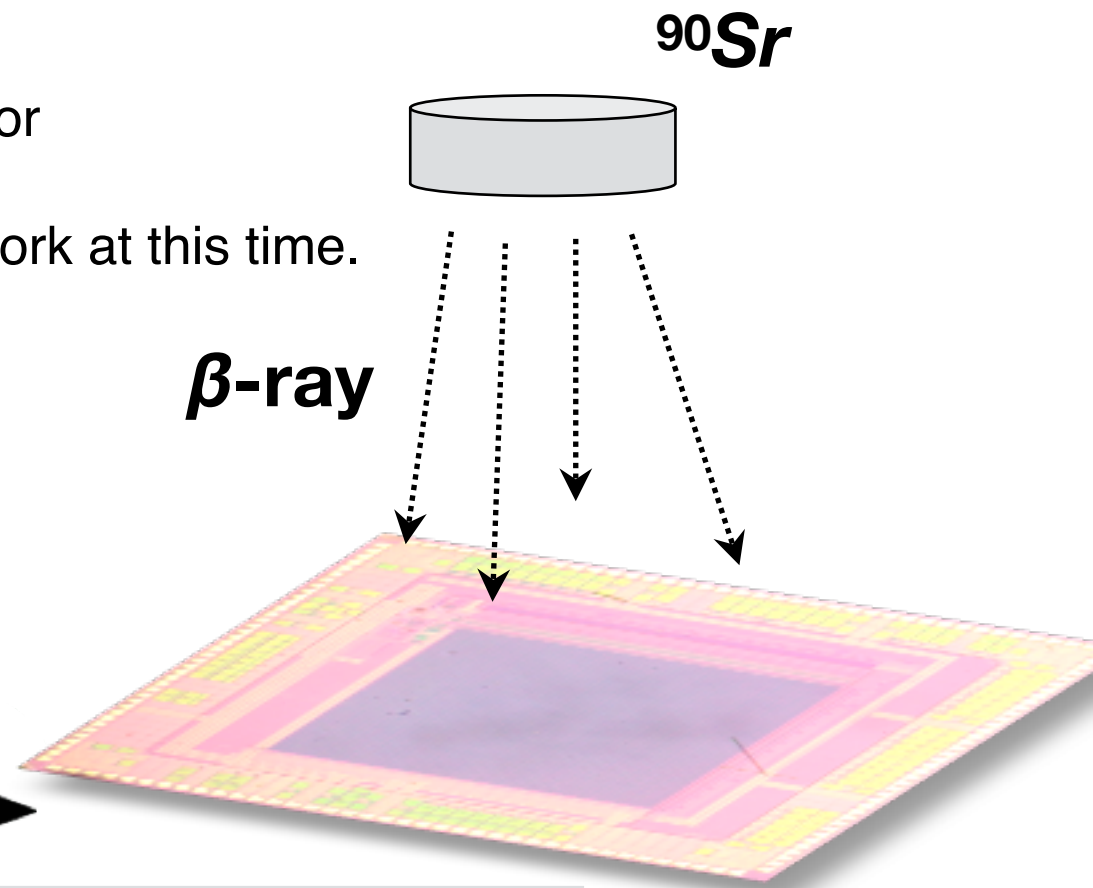
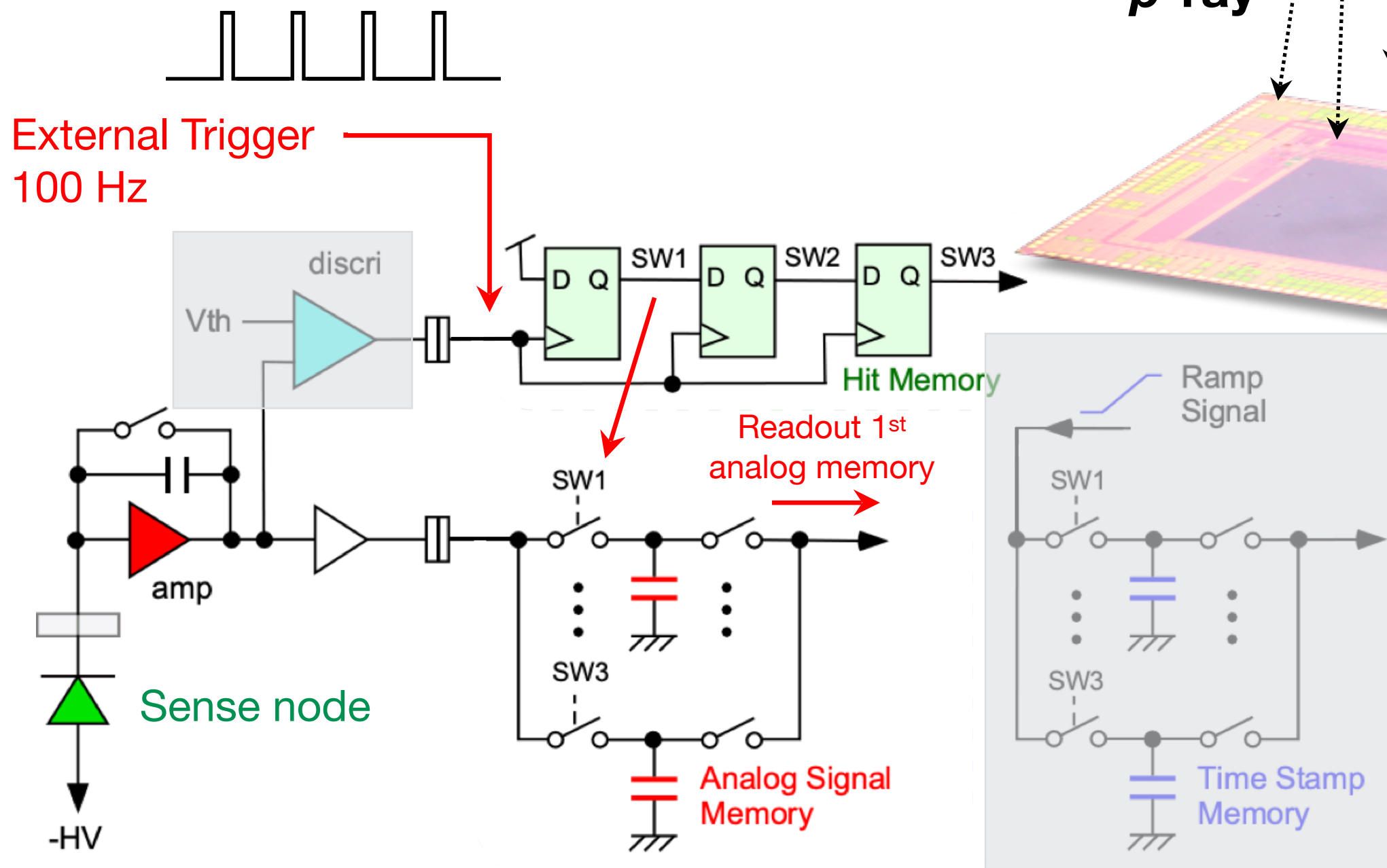
Total bumps: 32,448 for pixel array

3,520 for I/O cell

β -ray tracks

*The sensors we have evaluated were single-SOI FZ-n type sensor due to the process issue of the 3D integration.

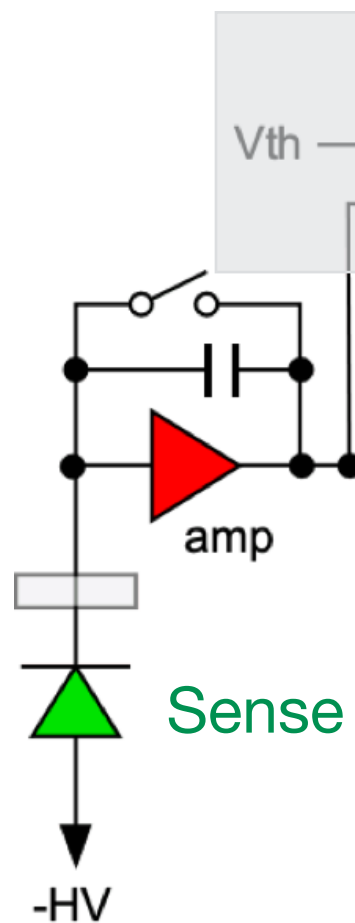
→ Comparator, Shift-register and Timestamp functions does not work at this time.



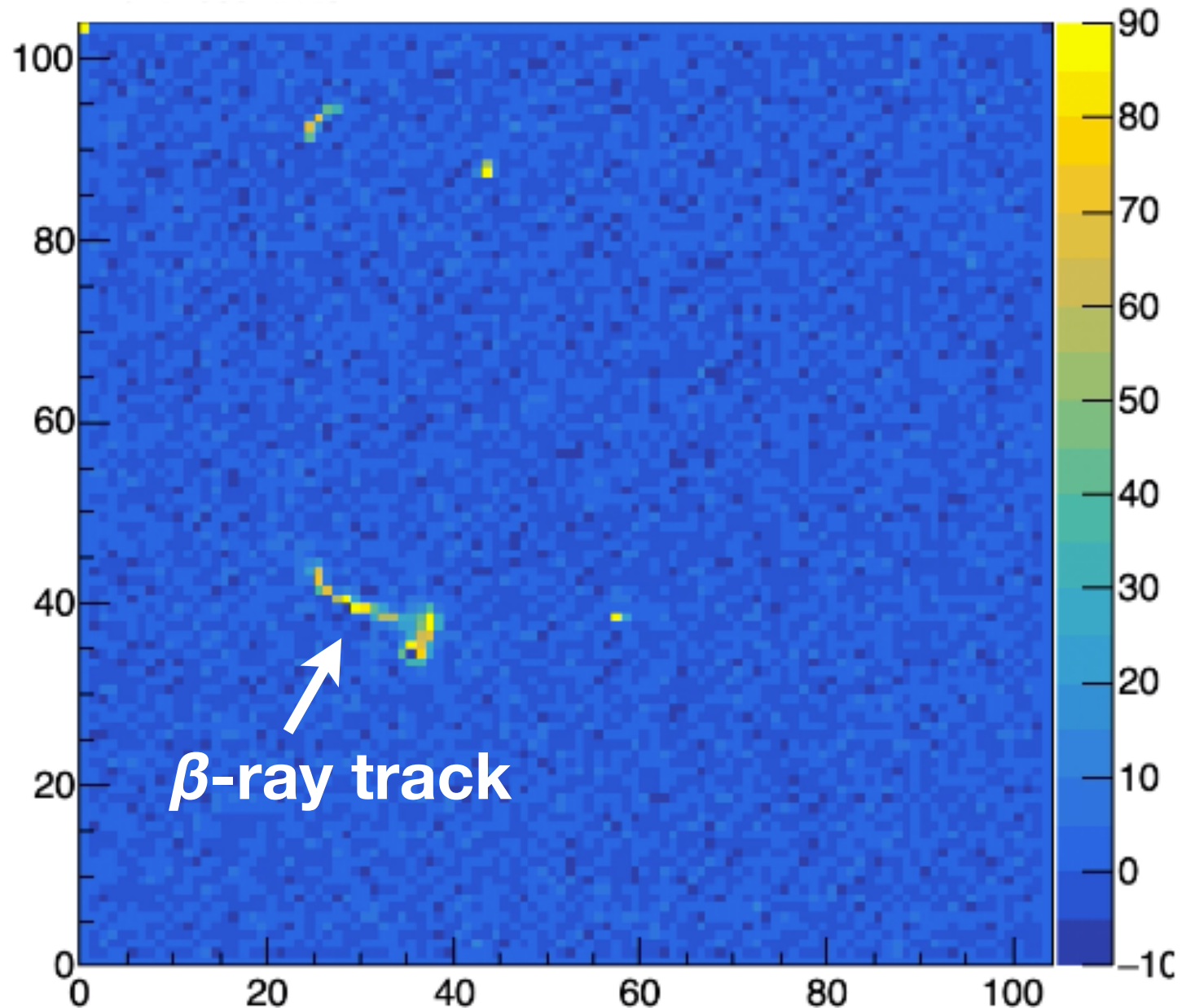
β -ray tracks

*The sensors we have due to the process i
→ Comparator, Shift

External Trigg
100 Hz



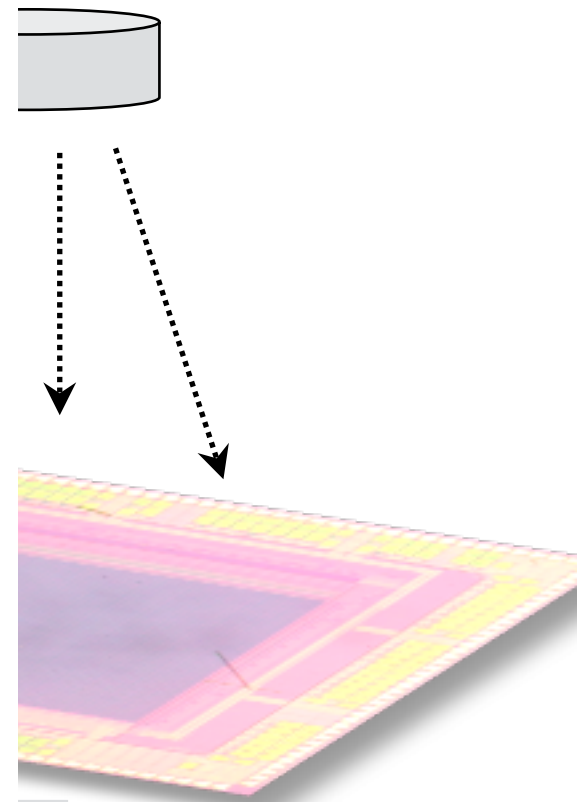
Row Address



Column Address

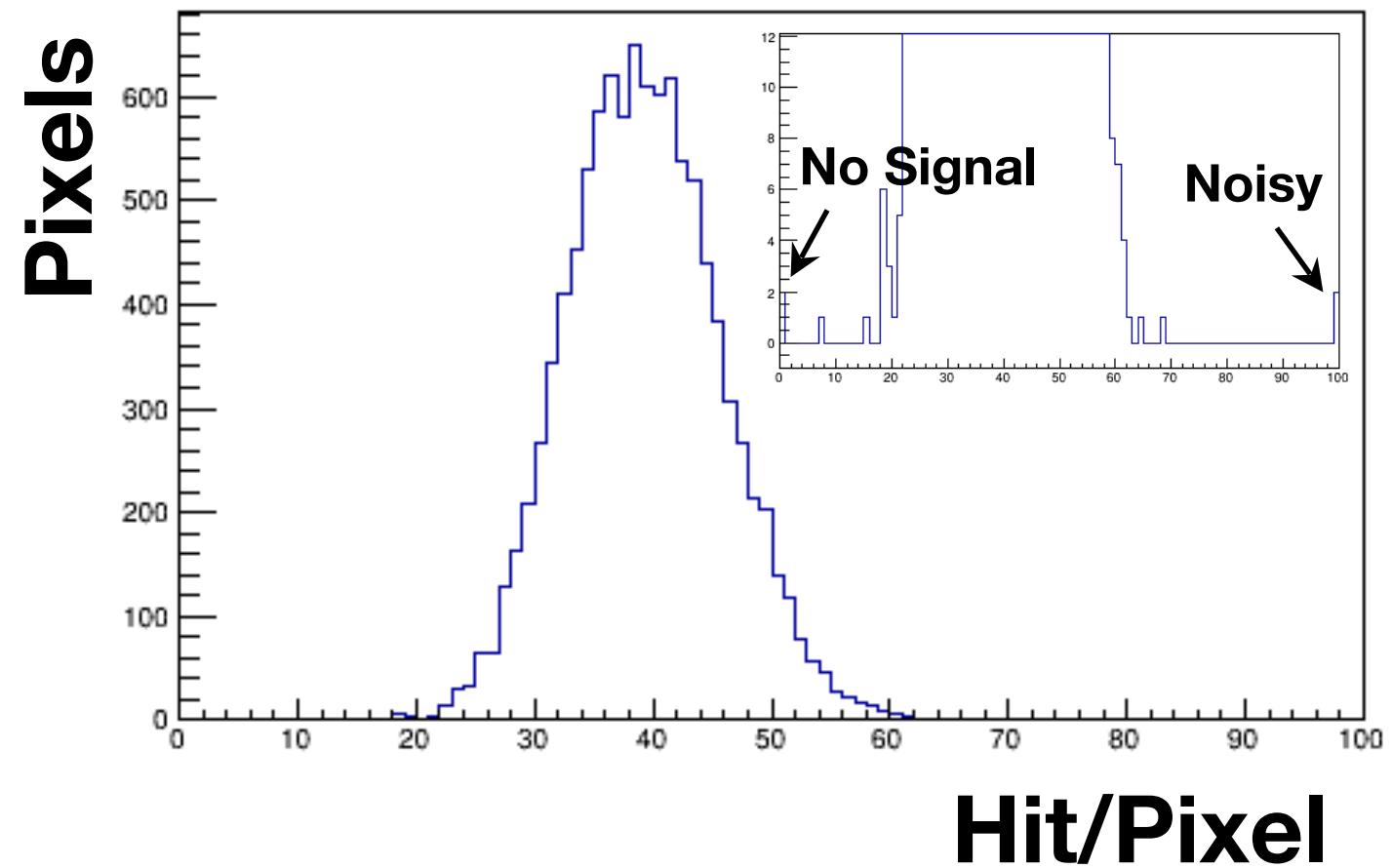
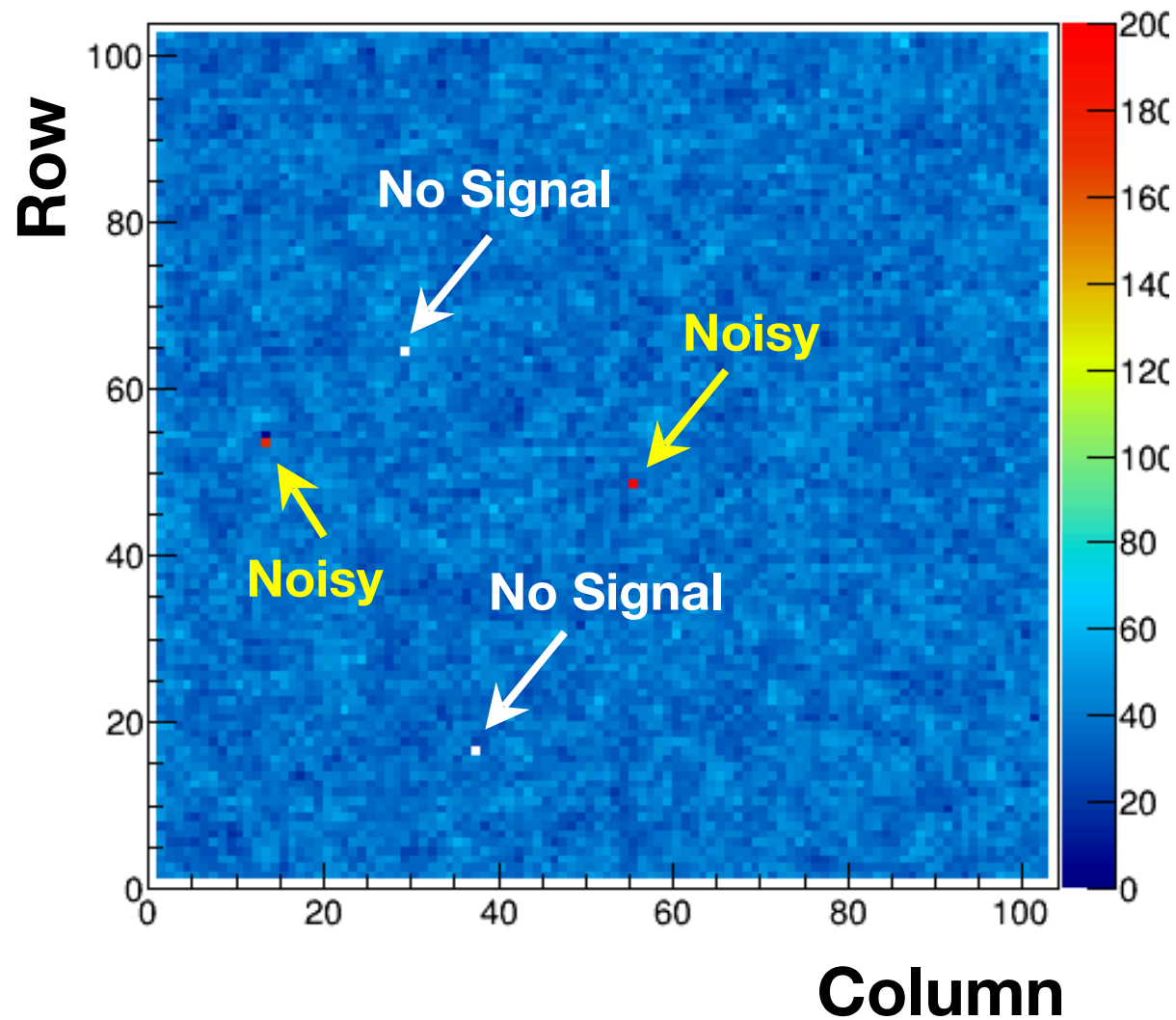
Analog Signal (ADC)

^{90}Sr



Bump Connection Yield

Hit Map (50 kEvents)



Connection Yield:
 $(102 \times 102 - 2) / 102 \times 102 \sim 99.98 \%$

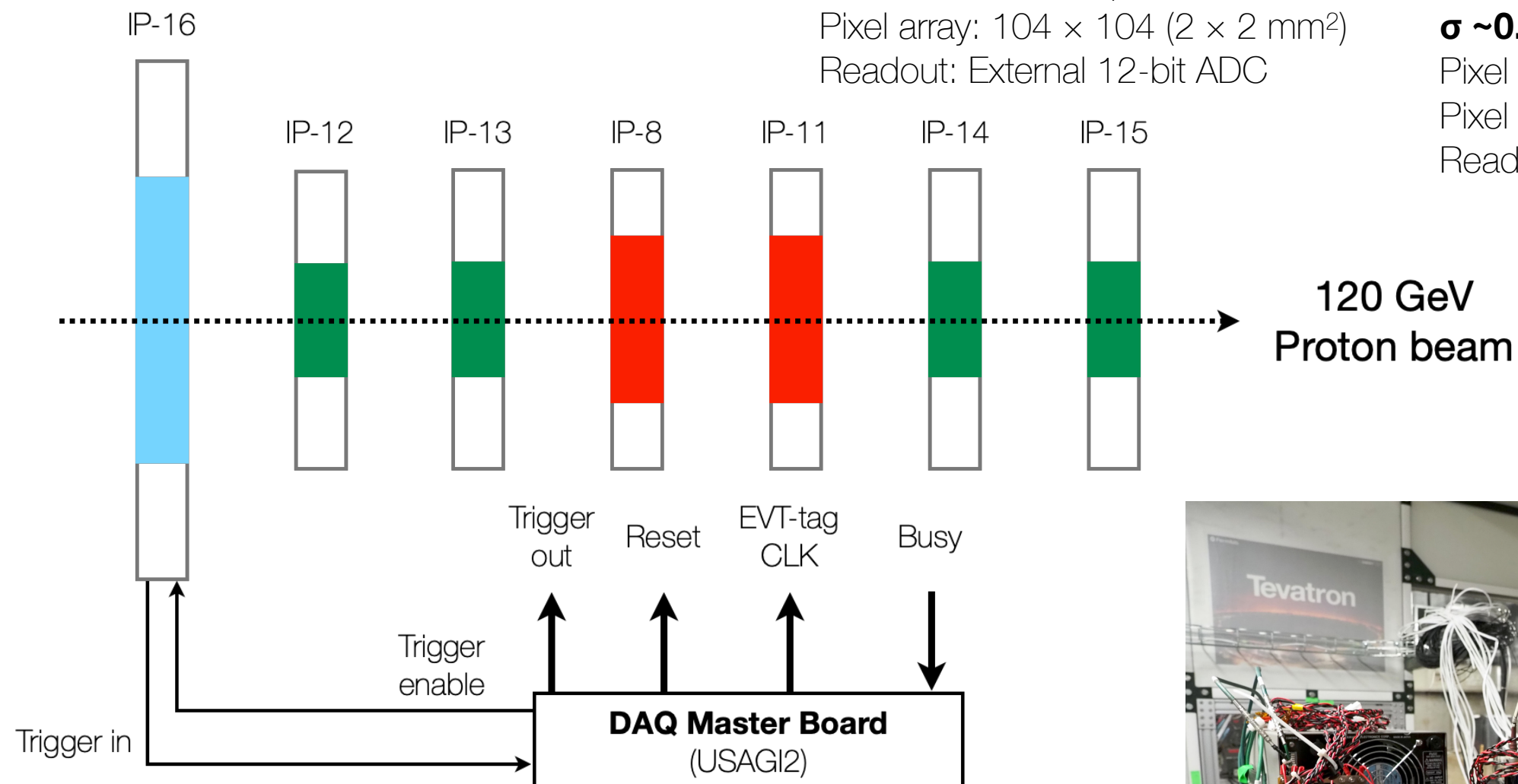
Reject the outermost pixels for the calculation.

Beam Test



Beam: 120 GeV proton (Fermilab Beam Test Facility)

DAQ rate: ~120 events/s



SOFIST4

Pixel size: $20 \times 20 \mu\text{m}^2$
Pixel array: 104×104 ($2 \times 2 \text{ mm}^2$)
Readout: External 12-bit ADC

FPIX2 (SOIPIX)

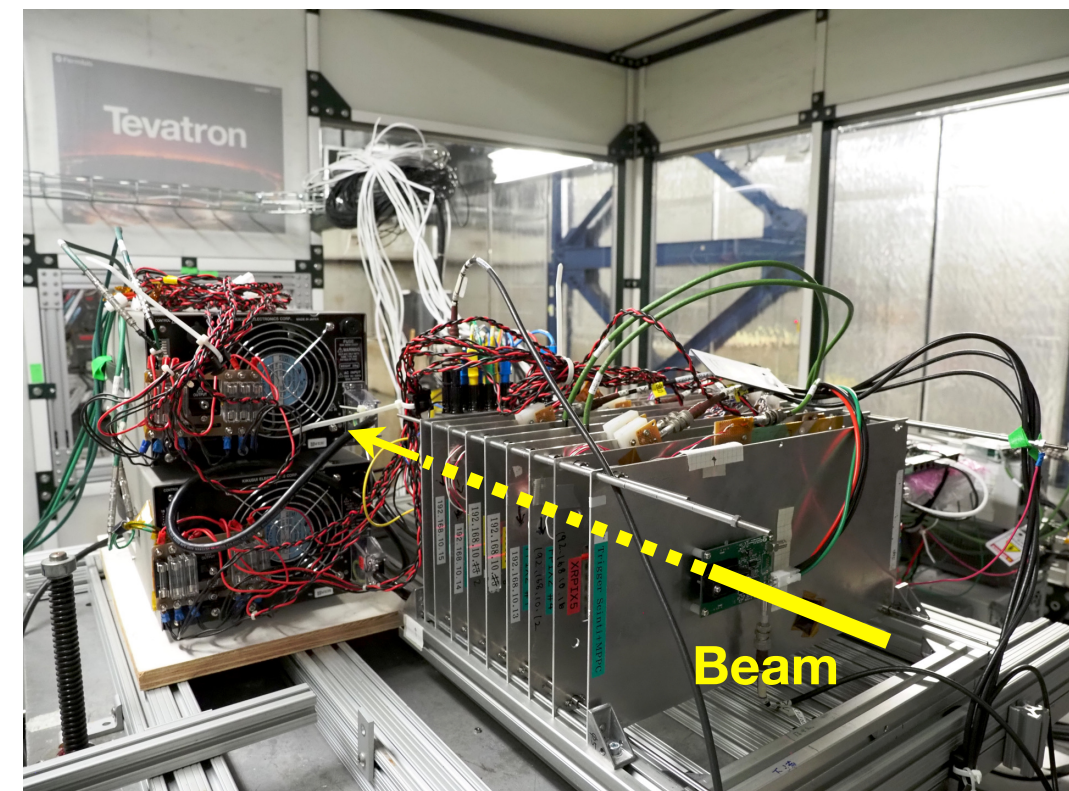
Telescope for SOFIST

$\sigma \sim 0.7 \mu\text{m}$

Pixel size: $8 \times 8 \mu\text{m}^2$
Pixel array: 128×128 ($1 \times 1 \text{ mm}^2$)
Readout: External 12-bit ADC

XRPIX5 (SOIPIX)

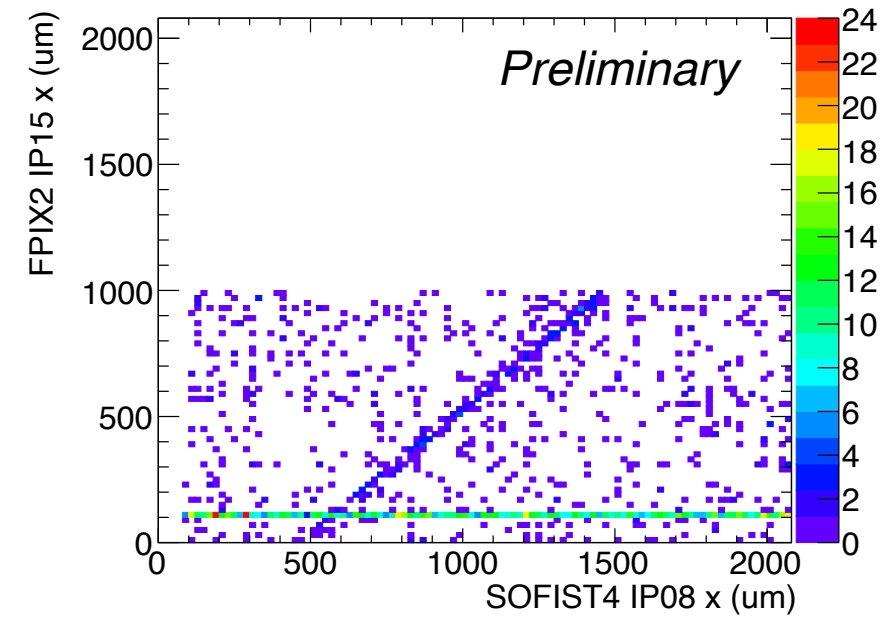
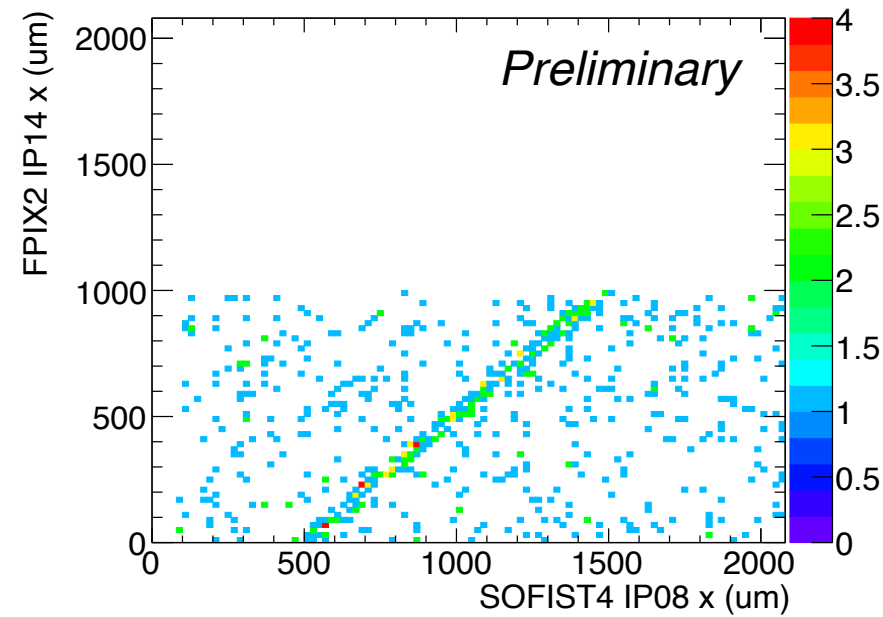
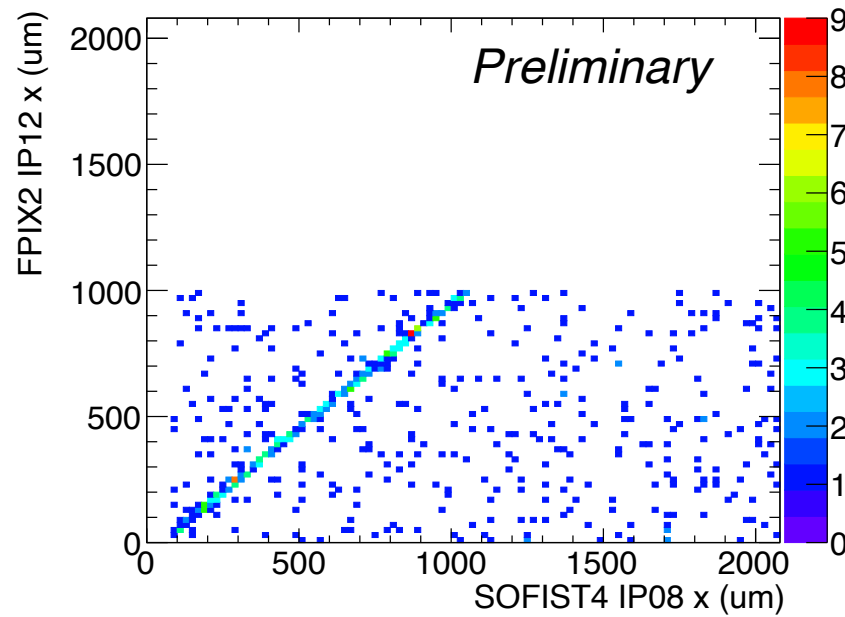
Trigger counter
Pixel size: $36 \times 36 \mu\text{m}^2$
Pixel array: 608×384 ($24.6 \times 13.8 \text{ mm}^2$)
Region of Interest function
Readout: External 12-bit ADC



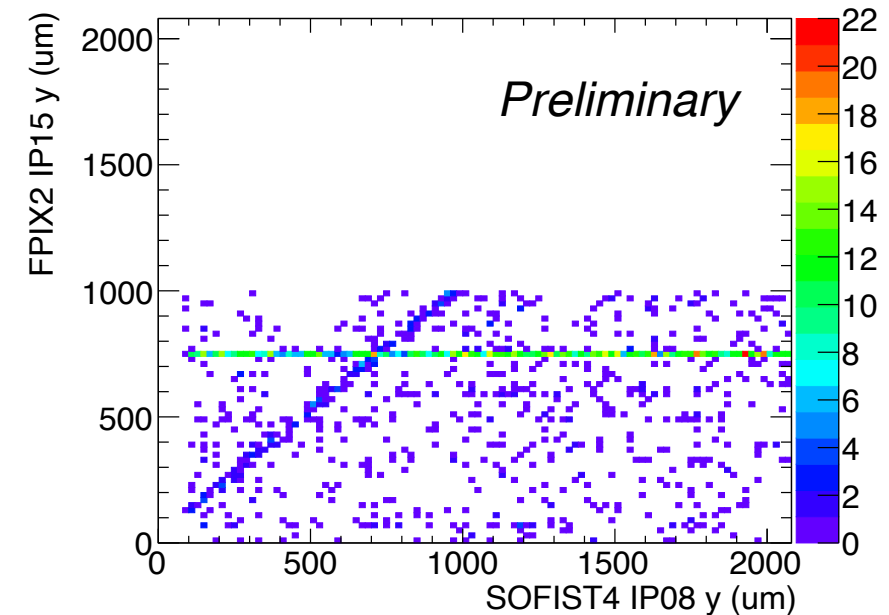
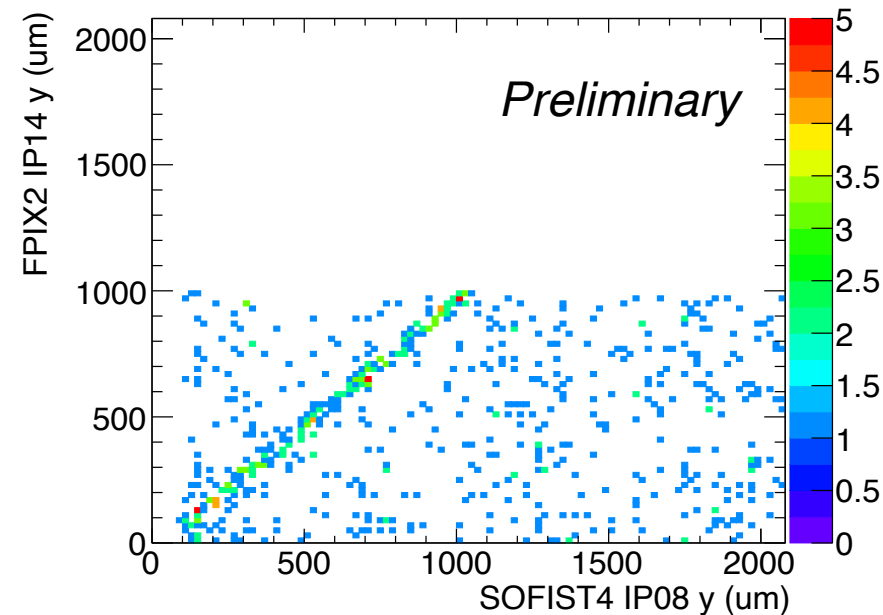
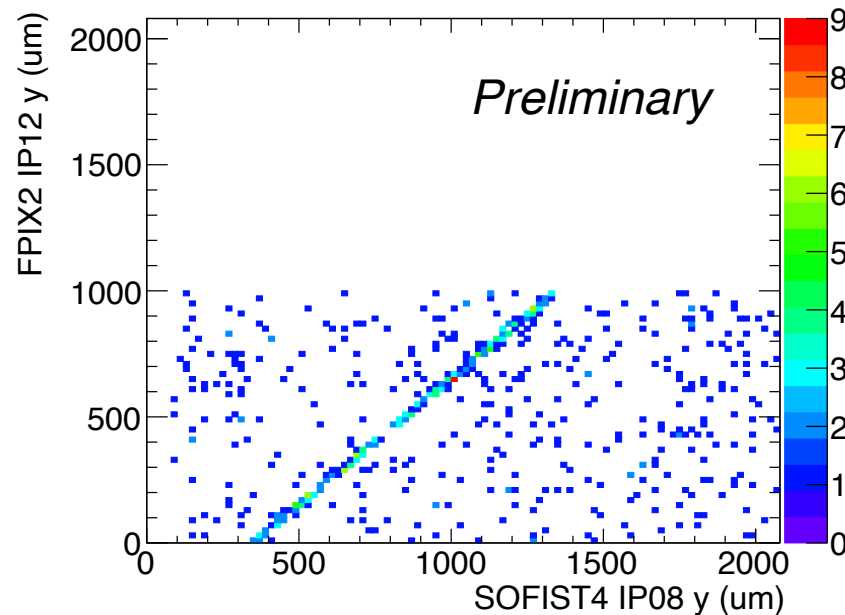
Hit Correlation

Hit position correction between **telescope (FPIX2)** and **SOFIST4 IP-8** in x and y-direction.

x-direction



y-direction

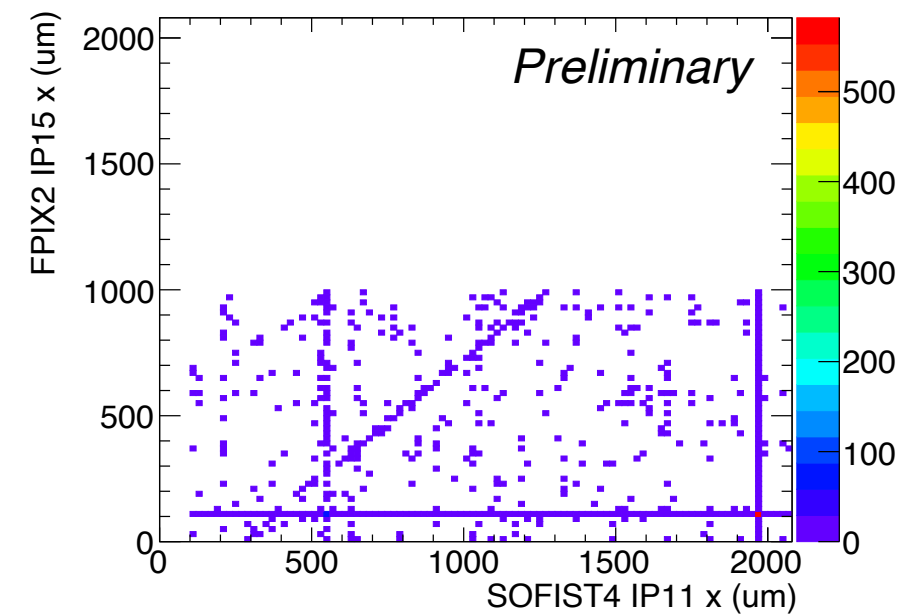
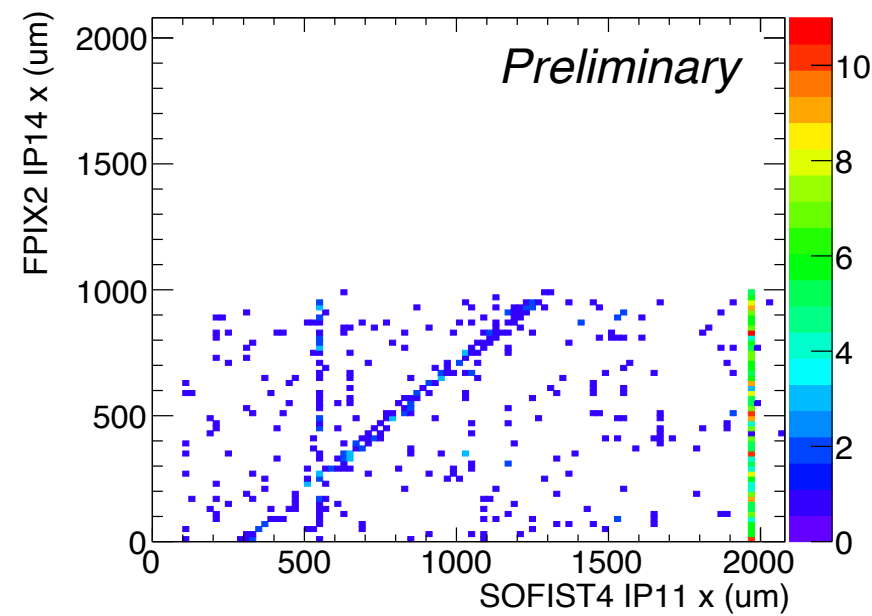
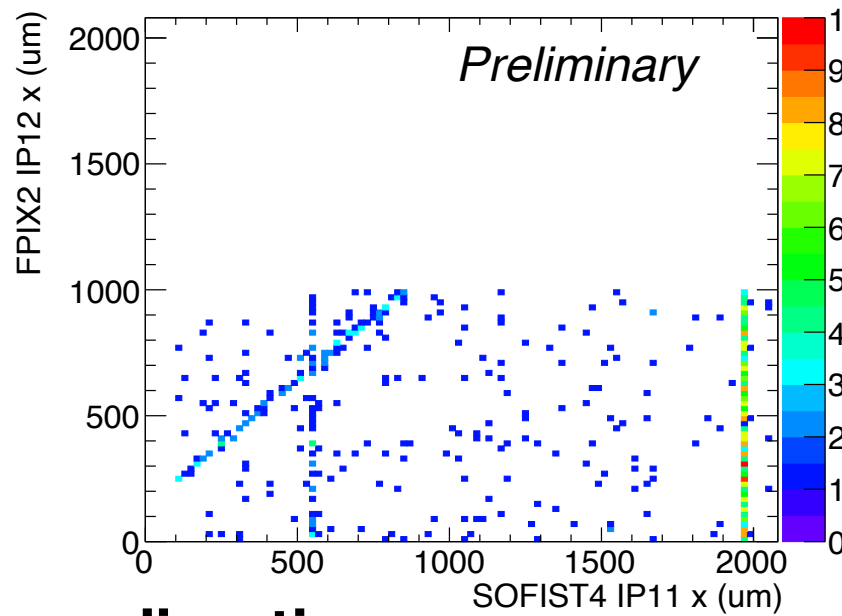


* **Active area:** FPIX2: $1 \times 1 \text{ mm}^2$, SOFIST4: $2 \times 2 \text{ mm}^2$

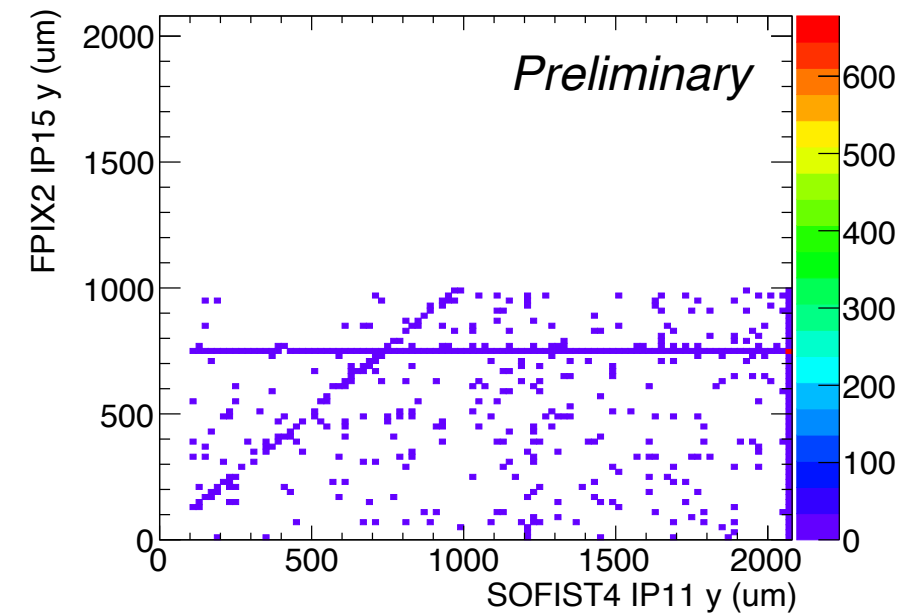
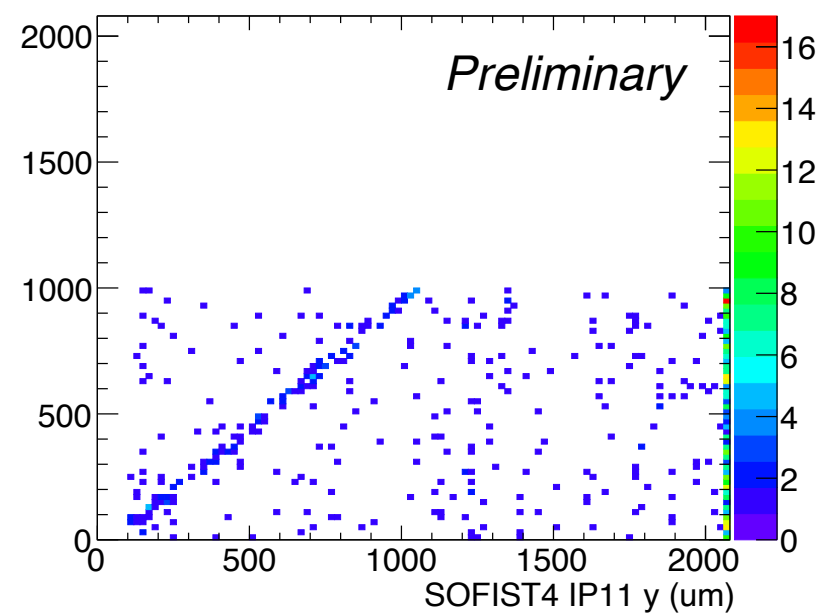
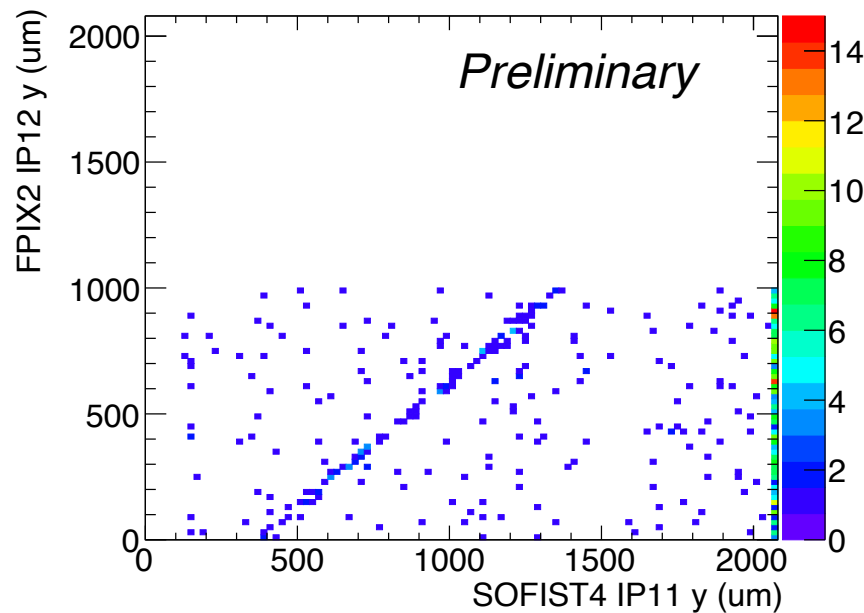
Hit Correlation

Hit position correction between **telescope (FPIX2)** and **SOFIST4 IP-11** in x and y-direction.

x-direction



y-direction

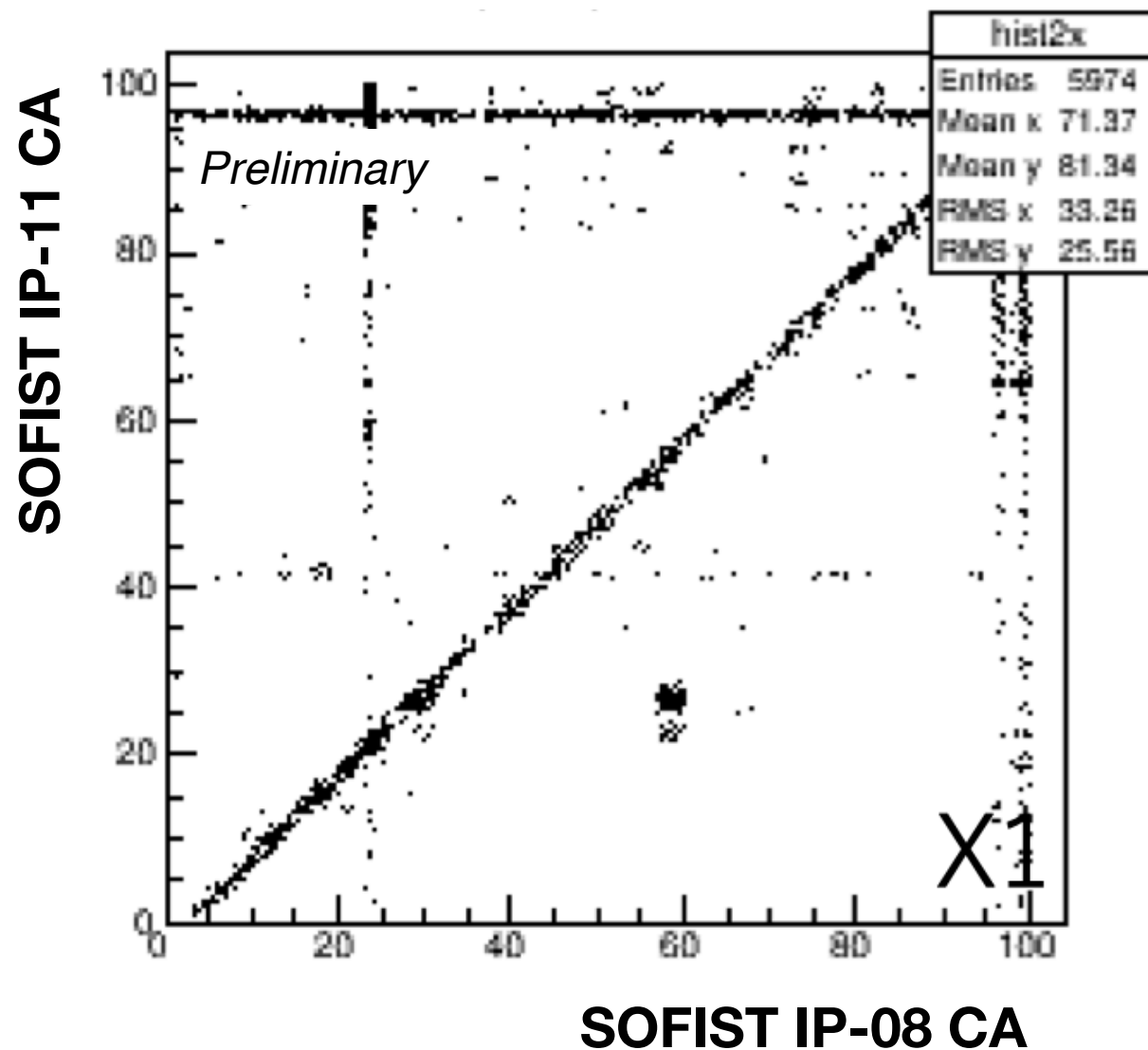


* **Active area:** FPIX2: $1 \times 1 \text{ mm}^2$, SOFIST4: $2 \times 2 \text{ mm}^2$

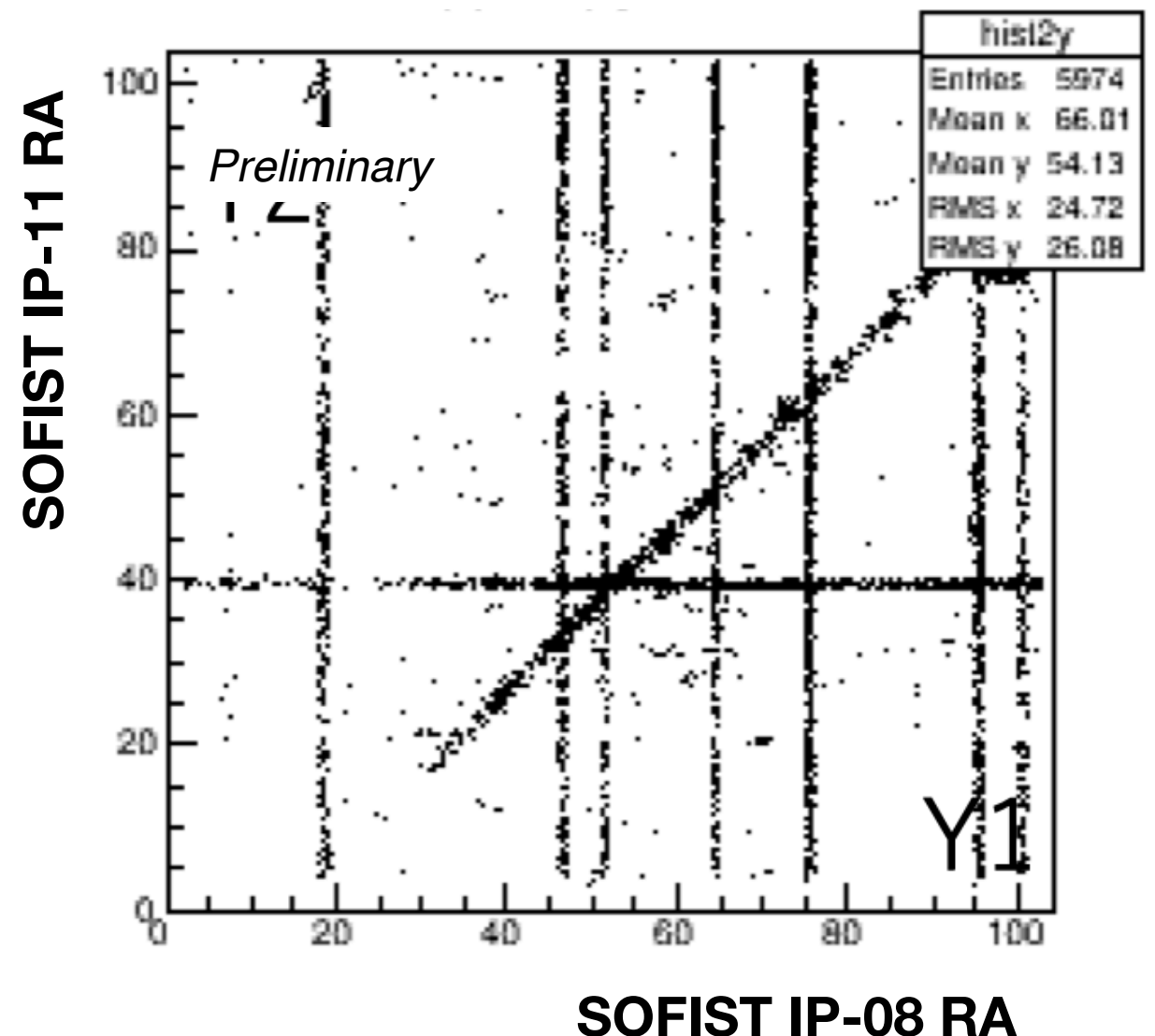
Hit Correlation

Hit position correction between **SOFIST4 IP-08** and **SOFIST4 IP-11** in x and y-direction.

x-direction



y-direction



Both SOFIST4 have successfully detected hit of proton beam and shown hit correlation between telescopes and SOFIST4 themselves.

SuperKEKB Upgrade

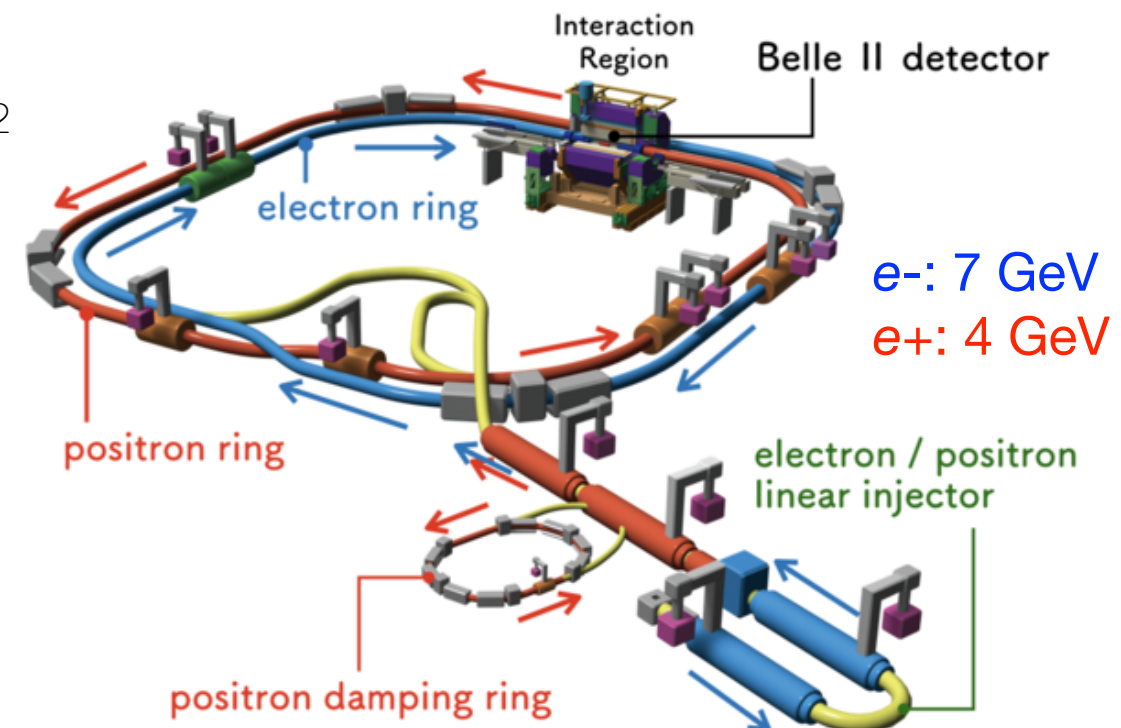
SuperKEKB: Target luminosity $8 \times 10^{35} \text{ cm}^{-2}\text{s}^{-1}$

SuperKEKB upgrade: 5 times higher luminosity (integrated luminosity: 250 ab^{-1})

→ 5 times higher beam background level (hit rate: 113 MHz/cm^2 at layer 1)

We propose new pixel detector for upgraded SuperKEKB

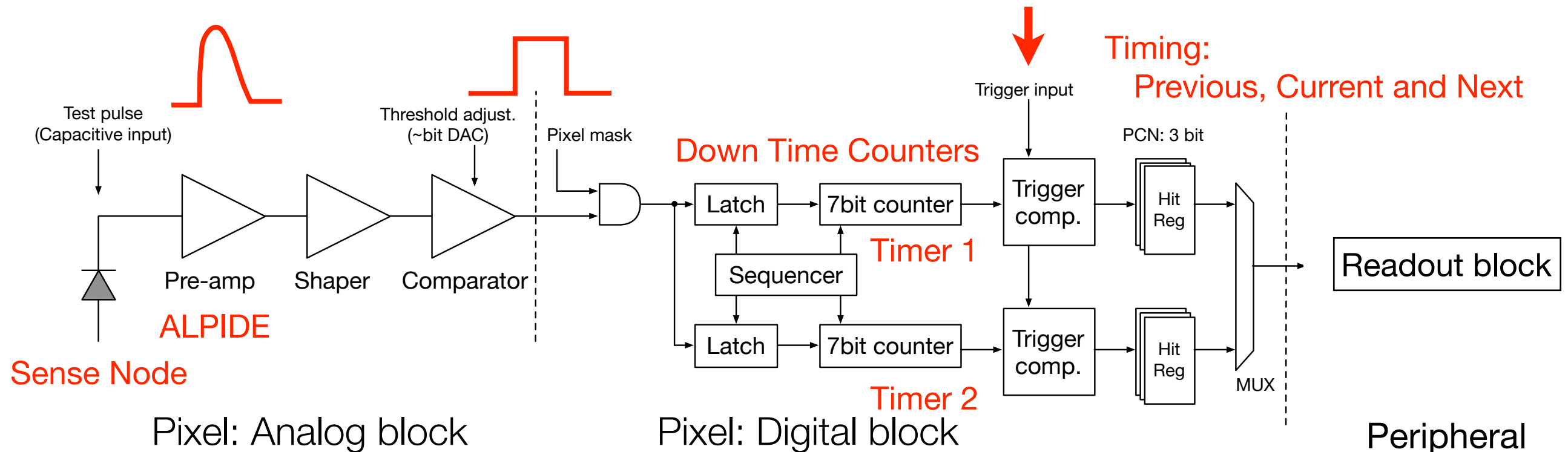
- much faster readout (trigger latency is $8 \mu\text{s}$)
- trigger based global shutter
- low occupancy $< O(0.1) \%$
- position resolution $\sim 10 \mu\text{m}$ (B mesons decay position inside beam pipe)
- low material budget (sensor thickness $\sim 50 \mu\text{m}$)
- radiation tolerance $\sim 100 \text{ Mrad}$, $5 \times 10^{14} n_{\text{eq}}/\text{cm}^2$



DuTiP Pixel Concept

DuTiP (Dual Timer Pixel)

Two down time counters for hits in a pixel



- 1) Analog block: usual configuration for the binary detector
- 2) Binary hit signal is sent from analog block (output of comparator) to digital block
- 3) Timer 1 starts counting down (7, 6, 5 ... μ s)
- 4) Hit timing is readout as current timing if the timer 1 = 1 when pixel received trigger decision
- 5) Timer 1 is reset if the trigger decision is not received at PCN timing
- 6) Timer 2 is used for second hit during trigger latency

Occupancy

Layer 1 hit rate = 113 MHz/cm², Trigger latency = 8 μ s: 0.012 %

DuTiP1 Pixel Design

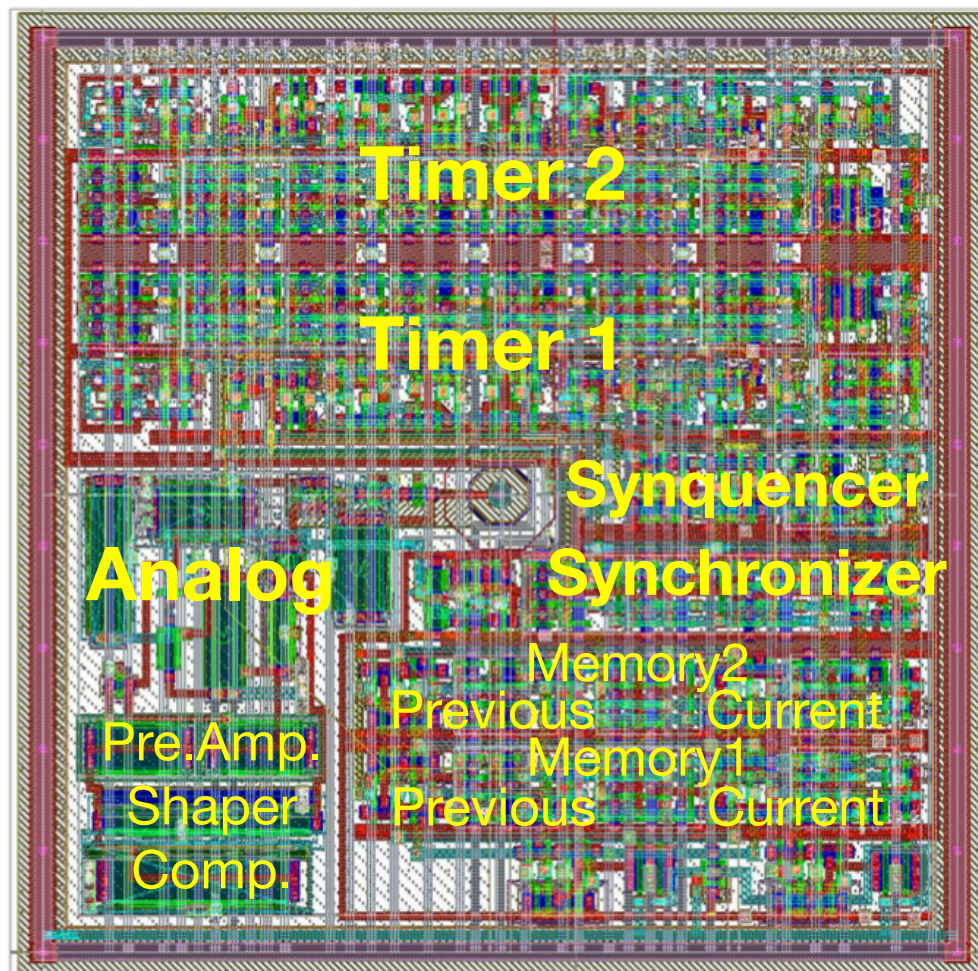
Pixel

- Pre. amplifier (ALPIDE type)
- Shaper
- Comparator
- Dual down time counters (7 bit)
- Timing memory (Previous/Current)

Readout

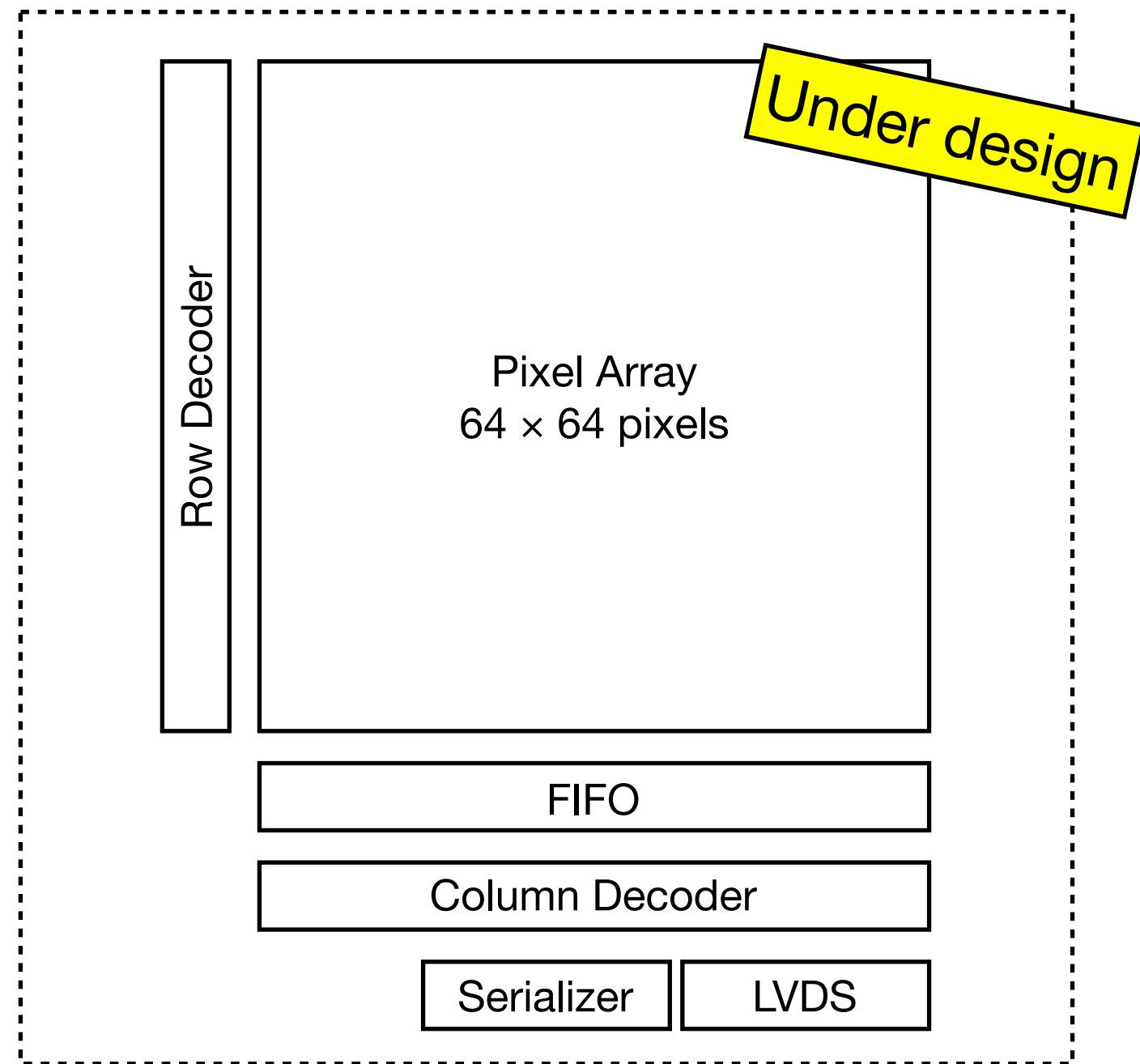
- Row address (5 bit), column address (5 bit)
- 2 bit hit (Previous/Current)
- Single 241 Mbps LVDS line

Pixel size: $45 \times 45 \mu\text{m}^2$



Chip Floor Plan

Chip size: $6 \times 6 \text{ mm}^2$ (Active area: $2.88 \times 2.88 \text{ mm}^2$)



We will submit DuTiP1 end of November in 2020.
Sensor will be thinned to $\sim 50 \mu\text{m}$ in 2021.

Summary

We are designing and developing a monolithic type pixel detector with SOI technology for the ILC vertex detector (SOFIST) and Belle II upgrade pixel detector (DuTiP).

SOFIST 3

Hit, analog signal and timestamp functions worked (infrared laser test).
Time resolution is $\sim 1.92 \mu\text{s}$ (120 GeV proton beam test).

SOFIST 4 (3D stacking sensor)

3D stacking bump connection yield $\sim 99.9 \%$
Successfully detected hits by 120 GeV proton beam.
Confirmed hit correlation between telescopes.
→ Still working on the beam test data analysis (alignment, tracking and position resolution).

DuTiP

Developing new pixel detector for Belle II upgrade.
First prototype DuTiP1 will be submitted in November 2020 (deliver: \sim Spring in 2021).